

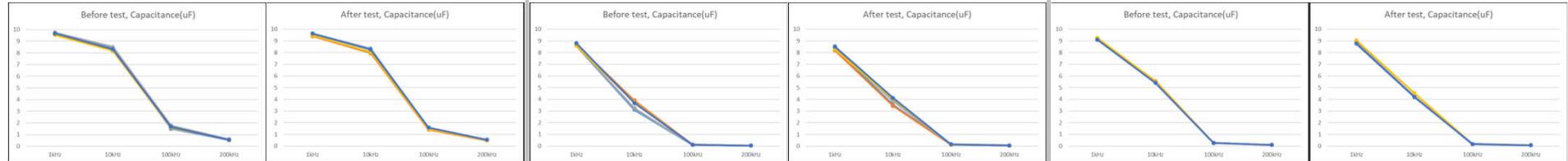
No.	Withstanding voltage(uA)
1	1
2	1
3	1
4	1
5	1

No.	Insulation resistance(MΩ)
1	0.01
2	0.01
3	0.01
4	0.01
5	0.01

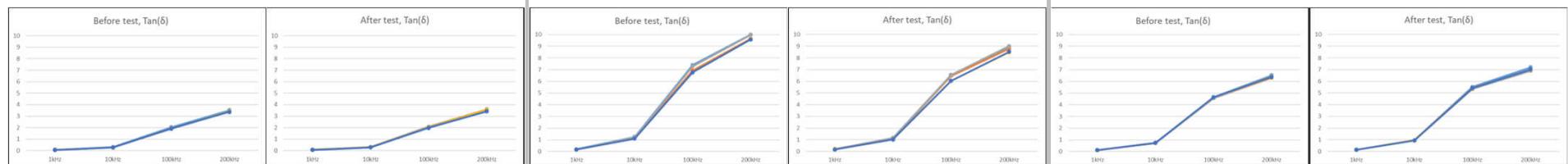
A/B/C社

High temperature test

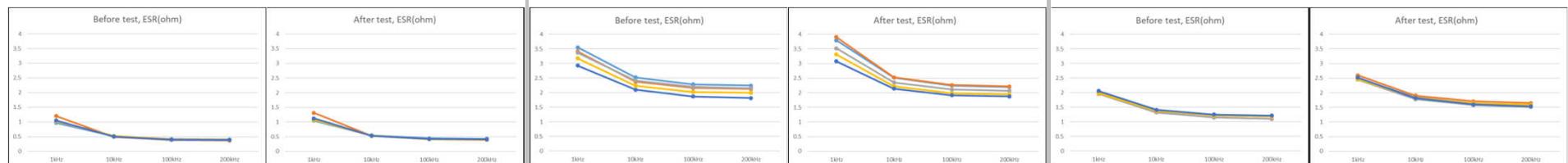
Capacitance(uF)



Tan(δ)

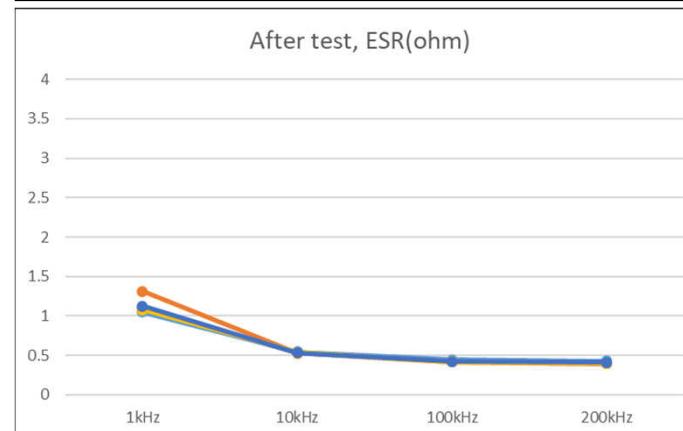
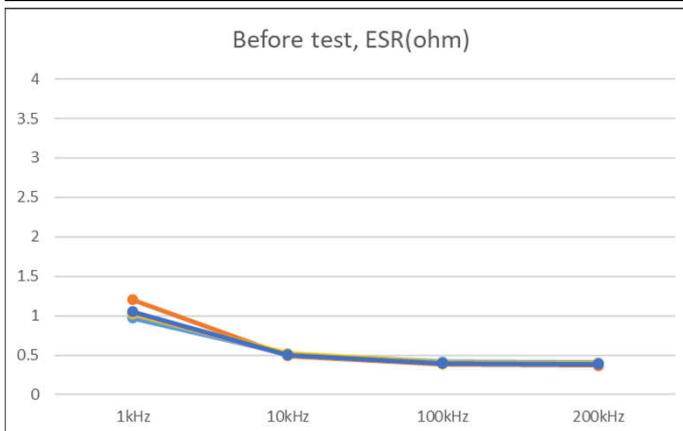
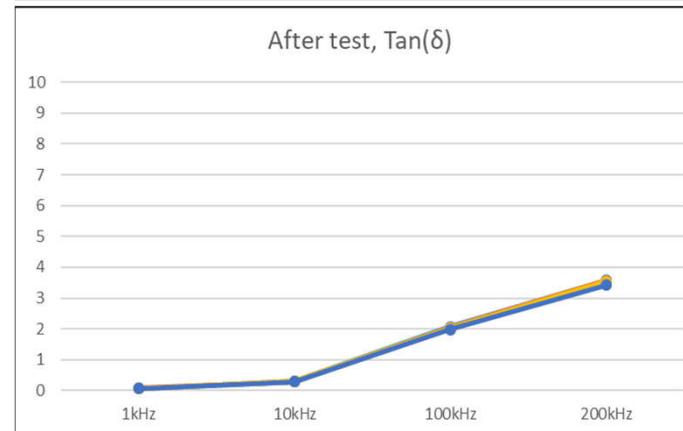
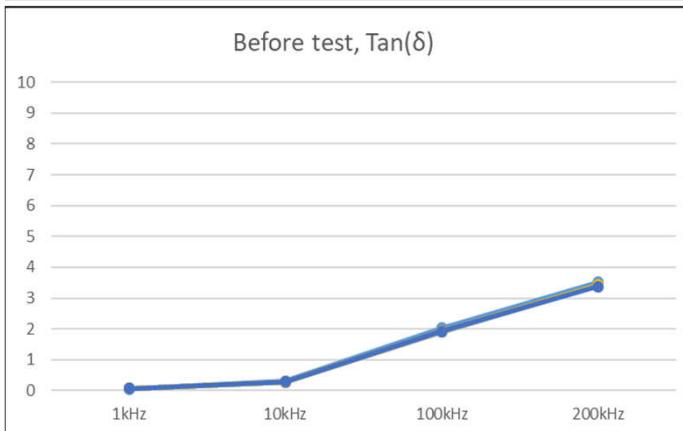
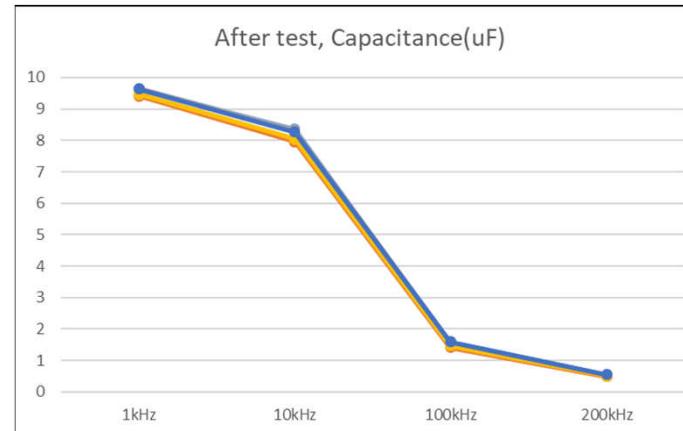
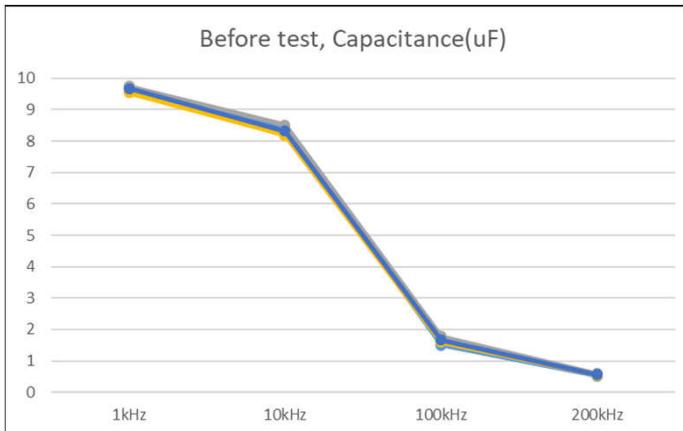


ESR(ohm)



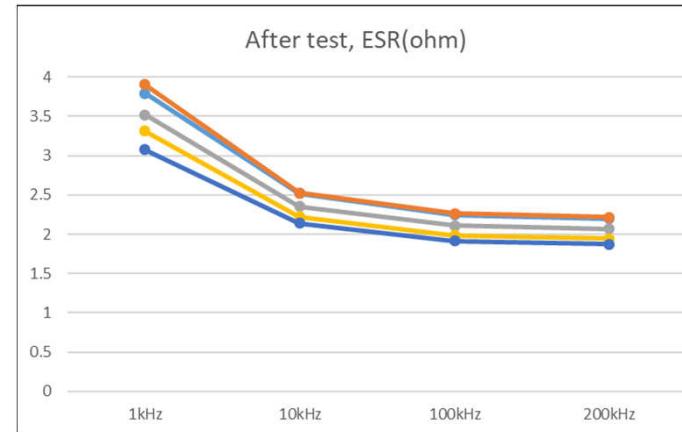
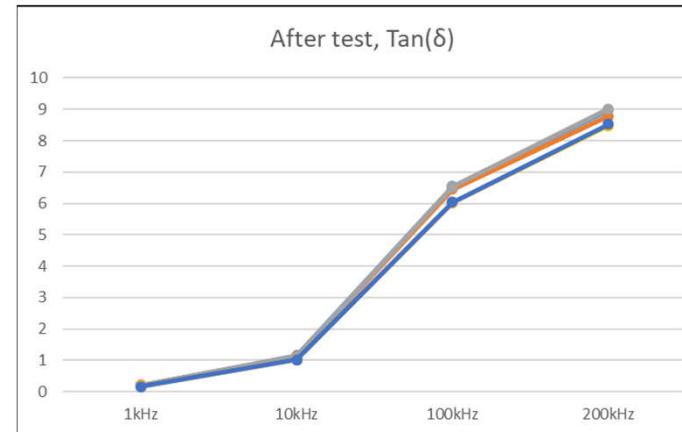
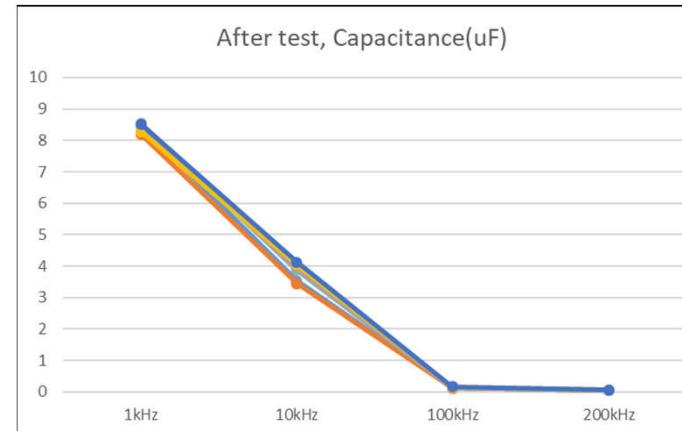
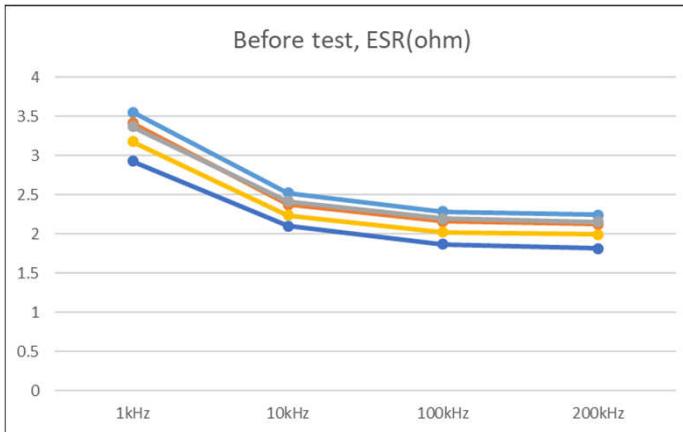
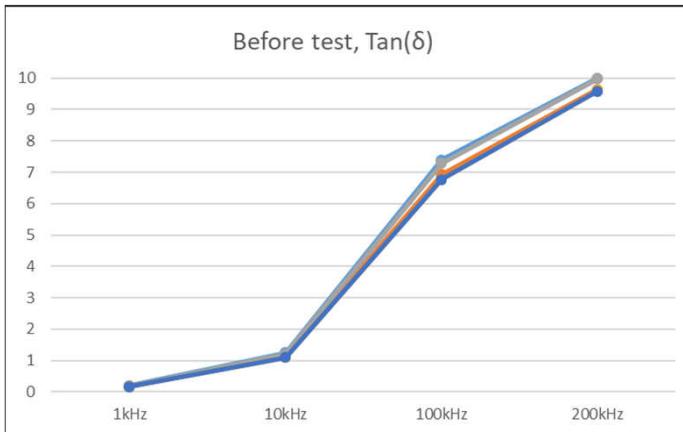
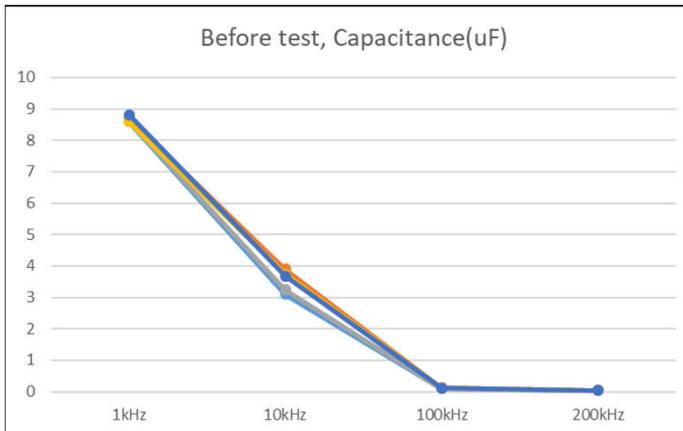
A社

High temperature test



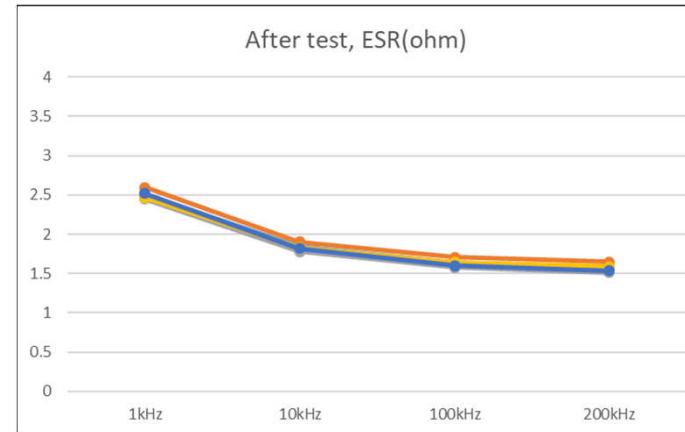
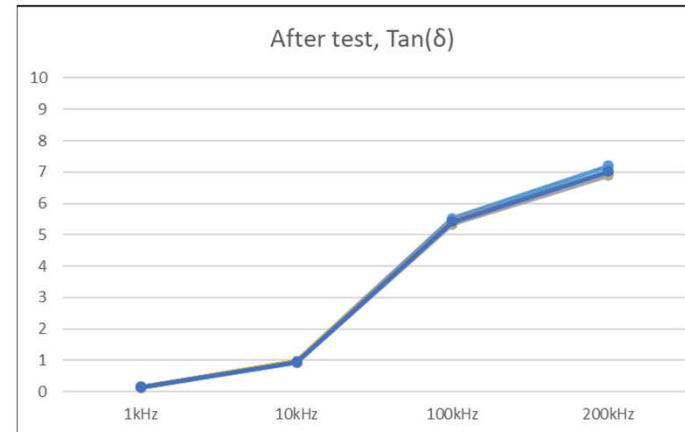
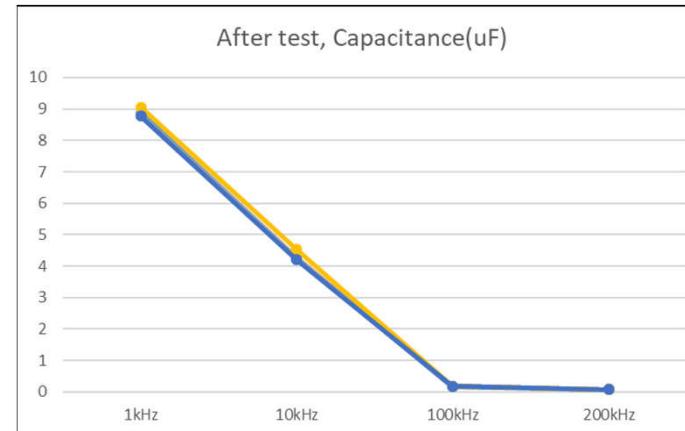
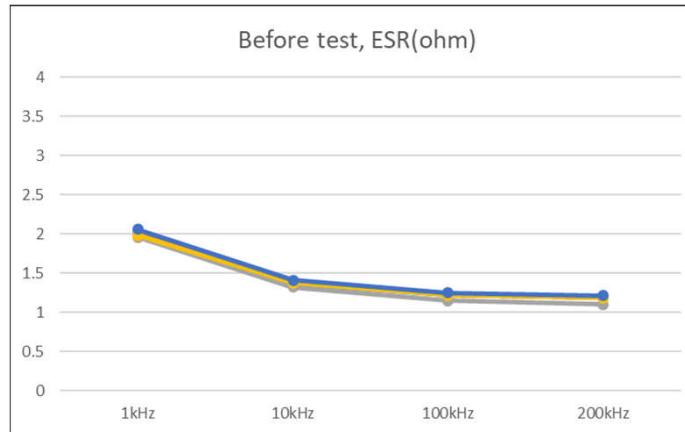
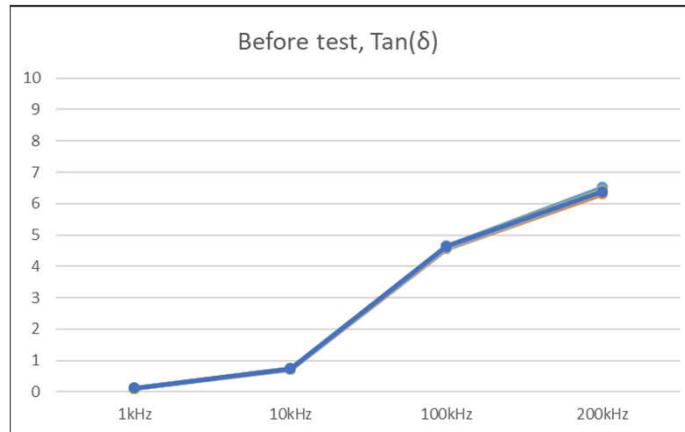
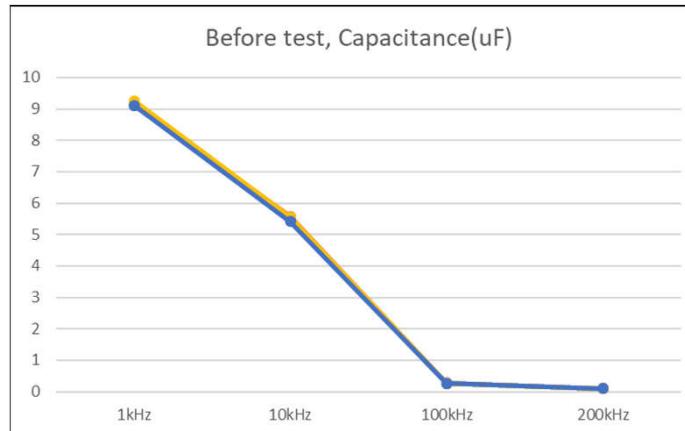
B社

High temperature test



C社

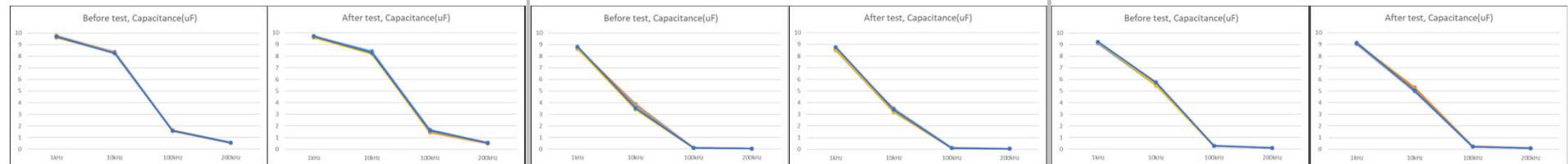
High temperature test



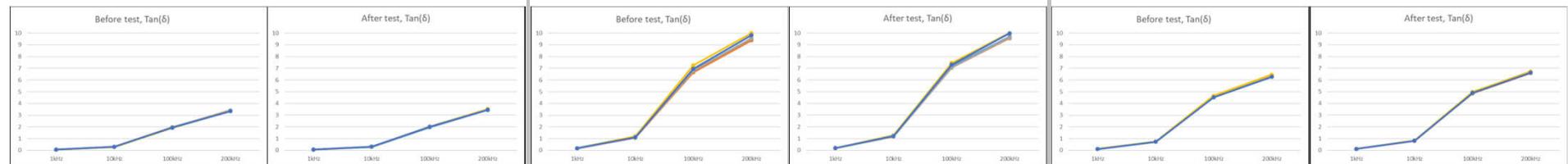
A/B/C社

Low temperature test

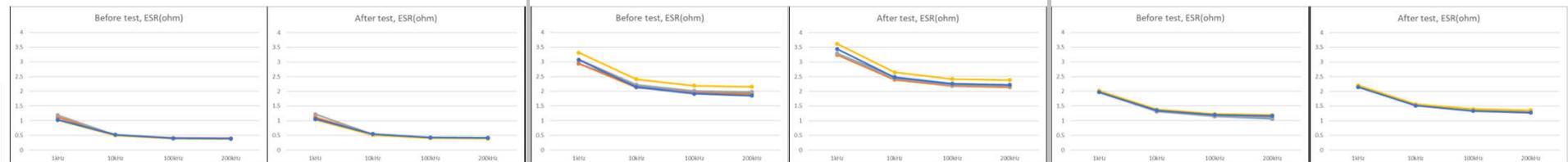
Capacitance(uF)



Tan(δ)

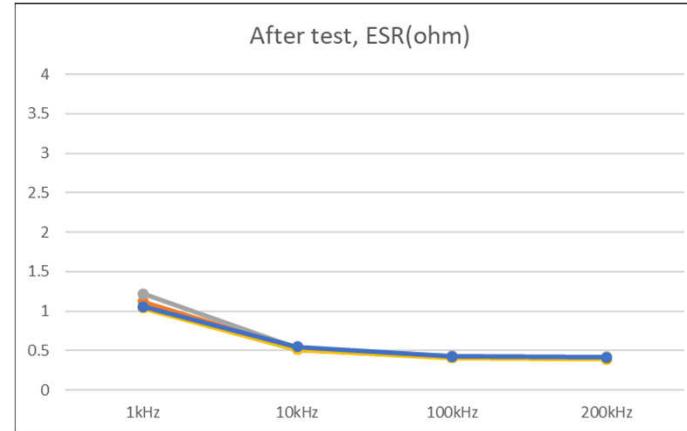
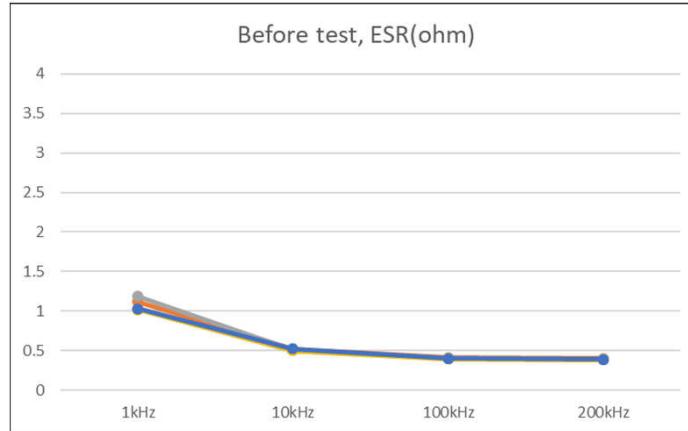
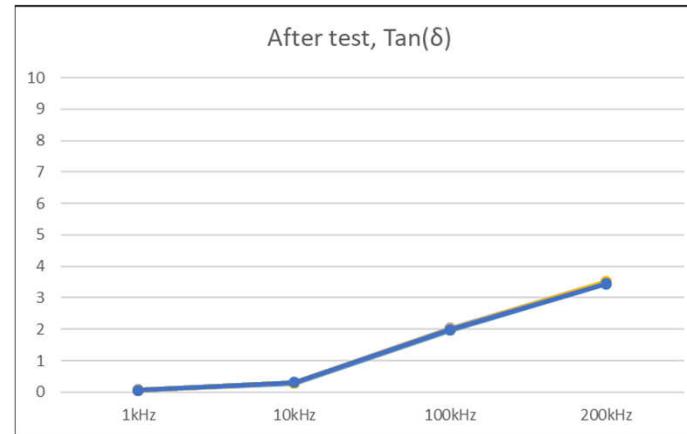
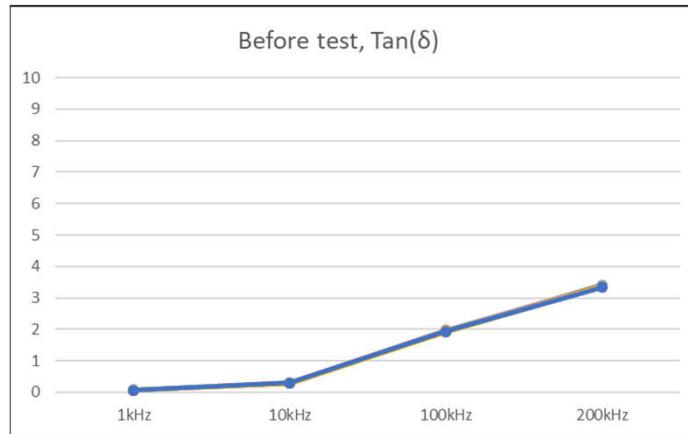
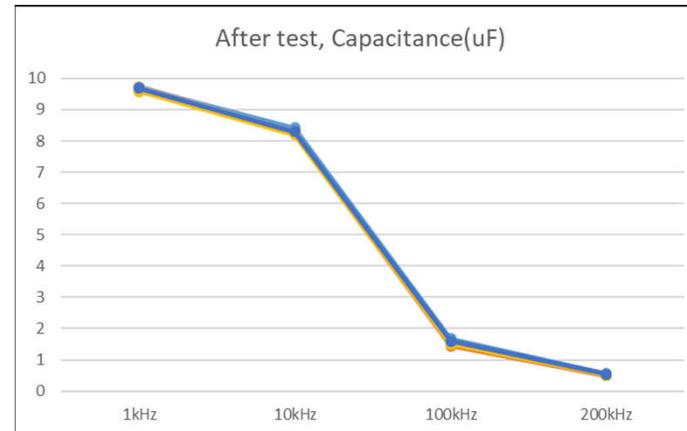
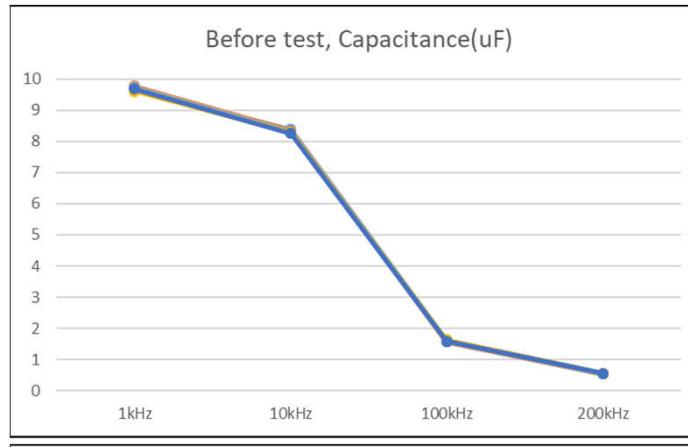


ESR(ohm)



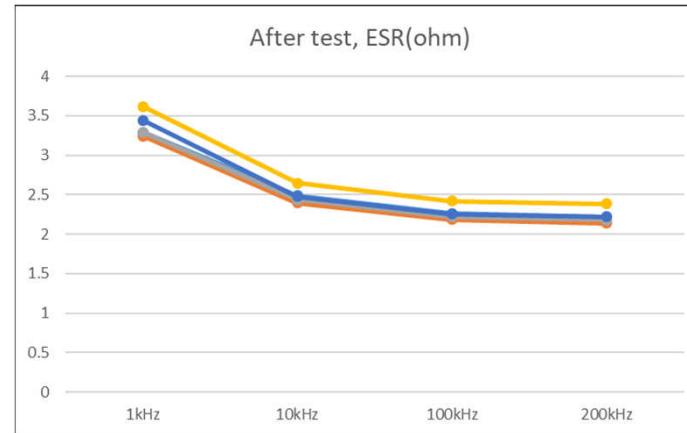
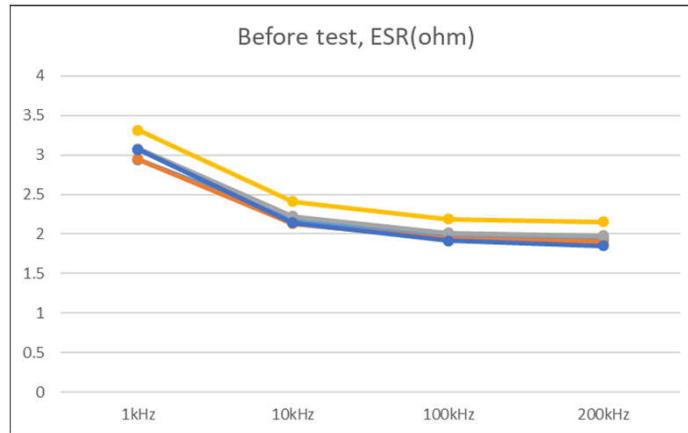
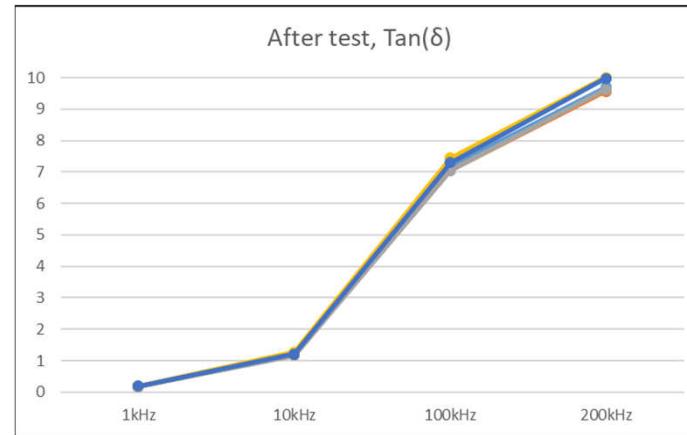
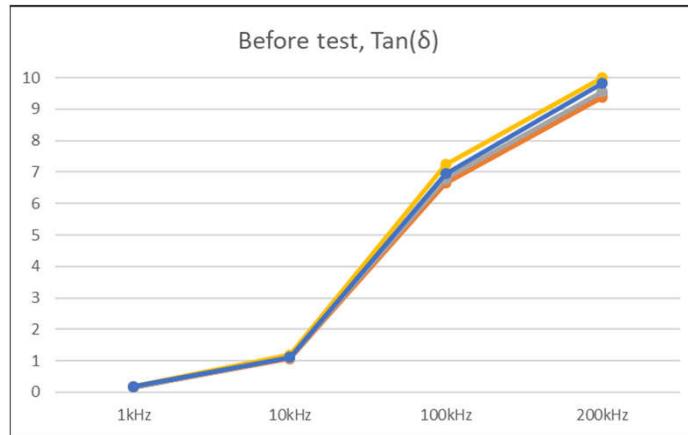
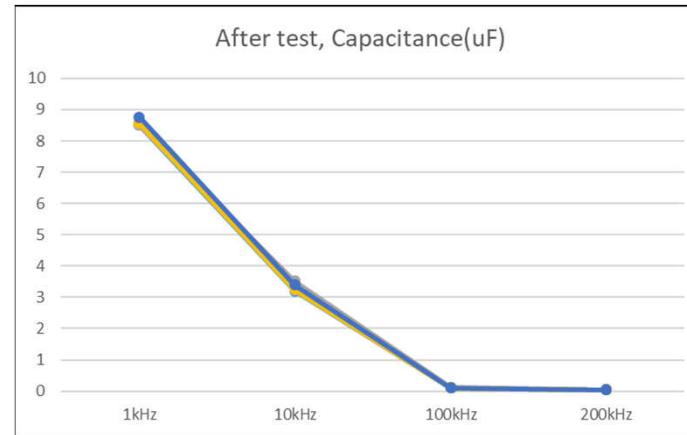
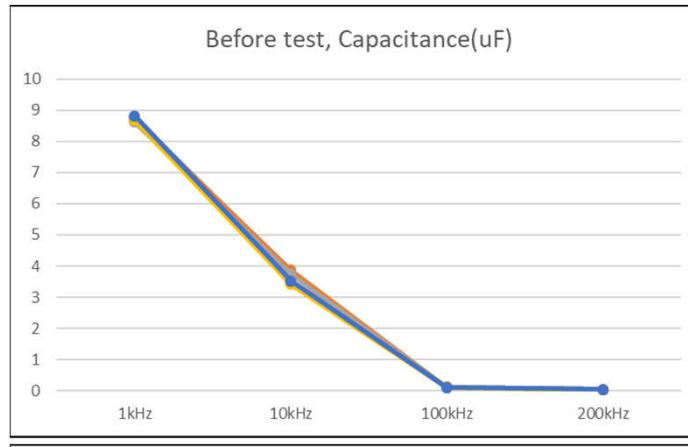
A社

Low temperature test



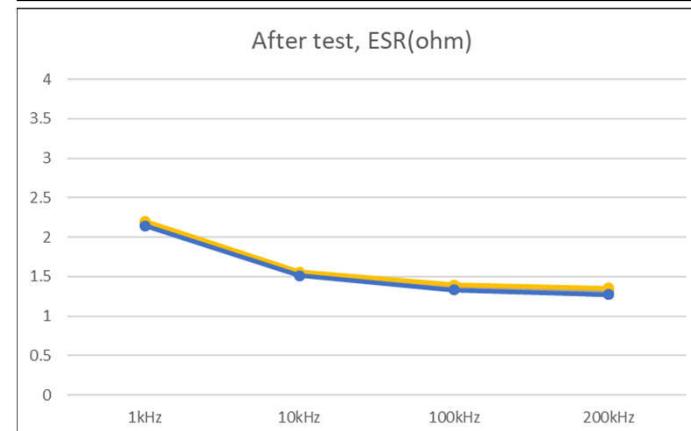
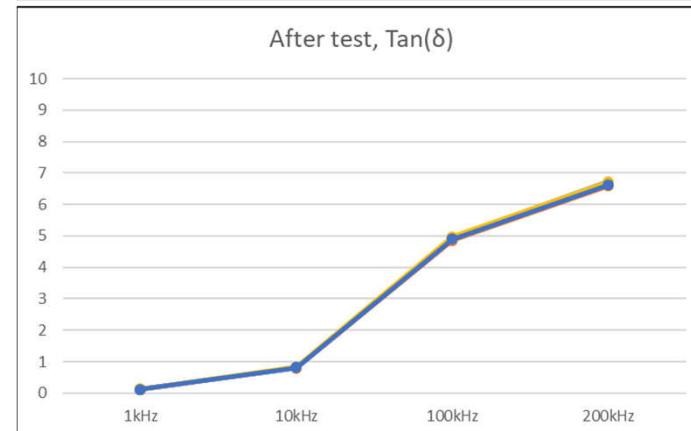
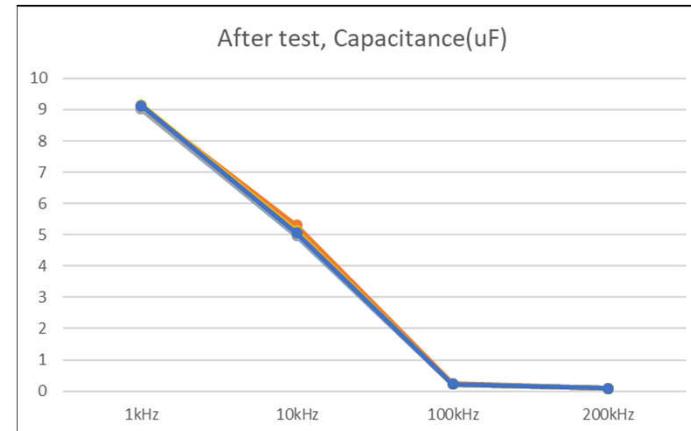
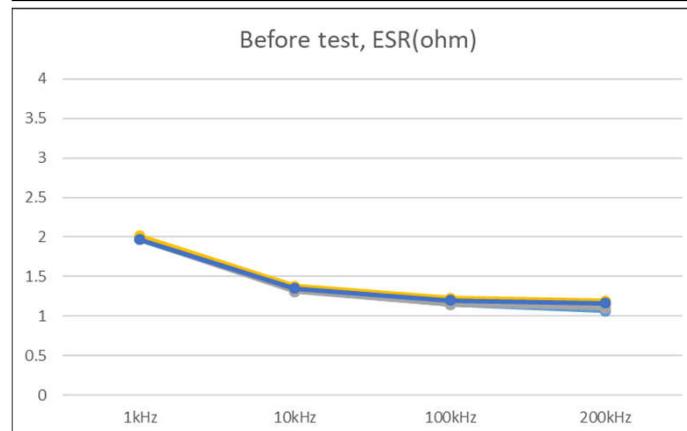
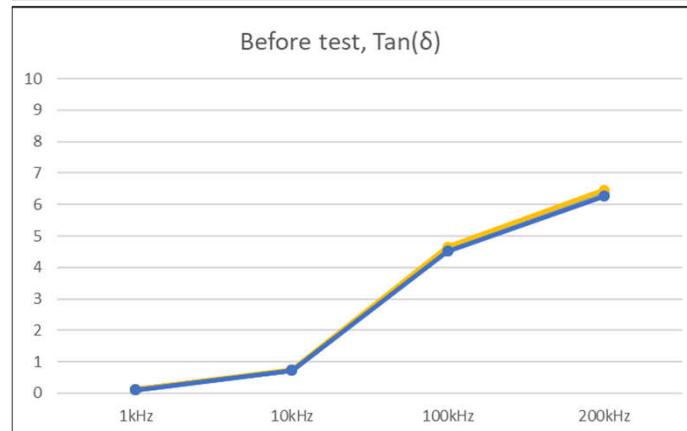
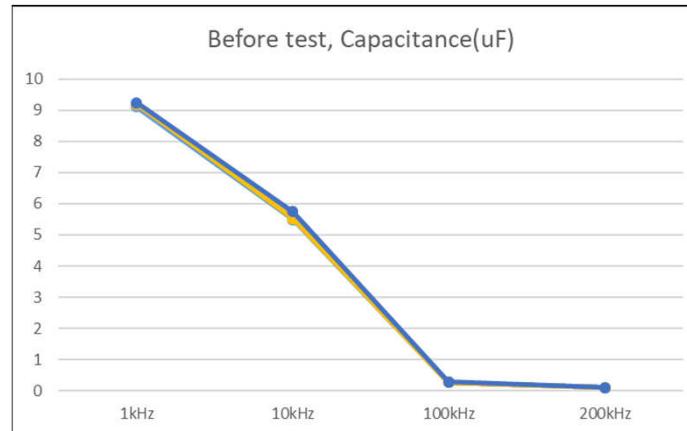
B社

Low temperature test

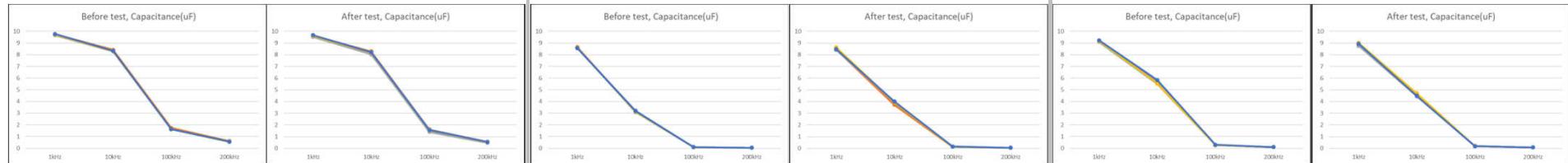


C社

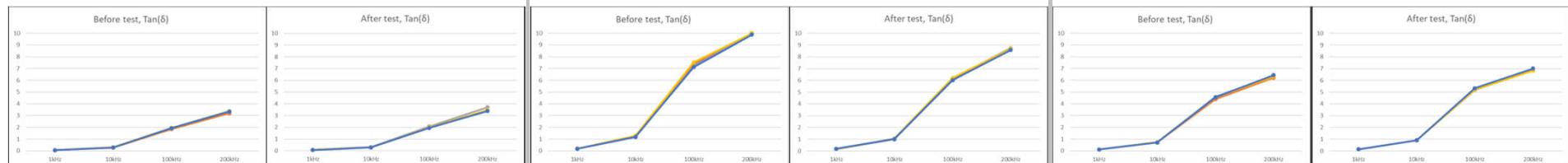
Low temperature test



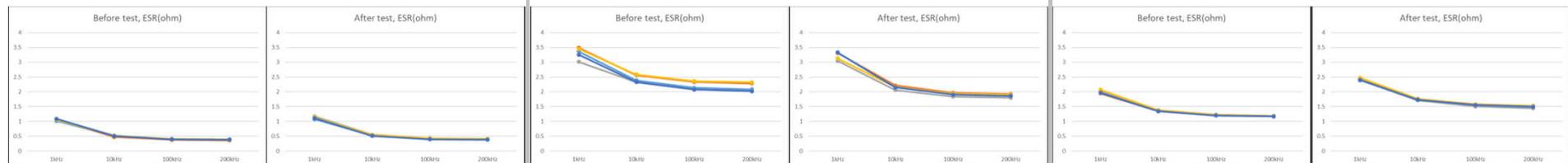
Capacitance(uF)



Tan(δ)

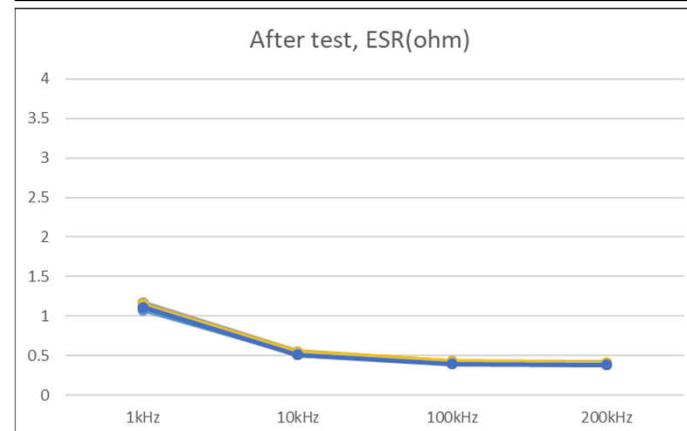
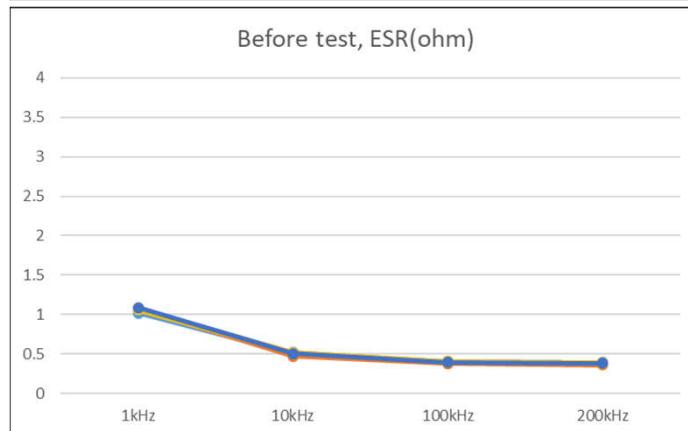
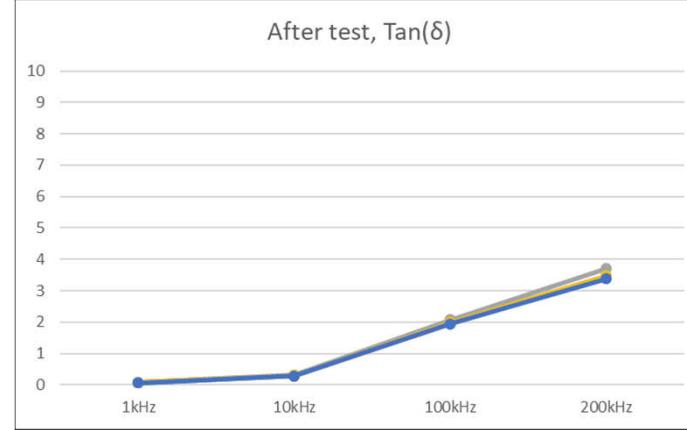
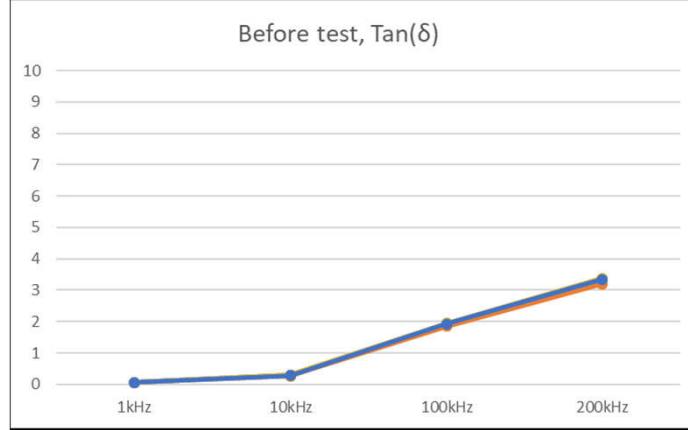
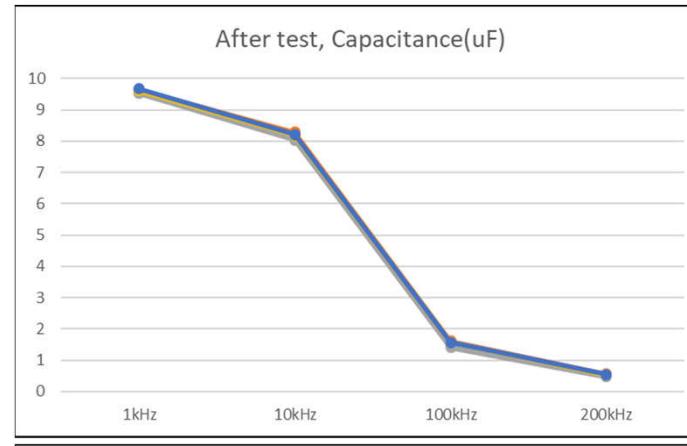
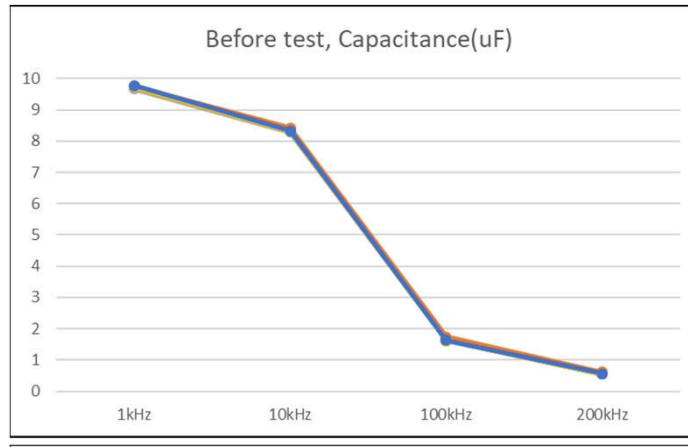


ESR(ohm)



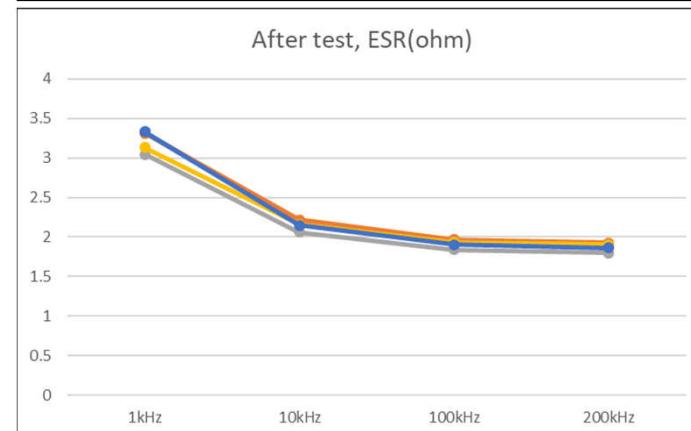
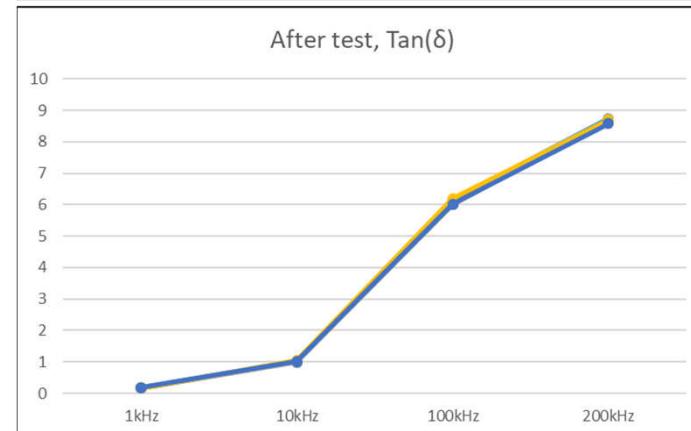
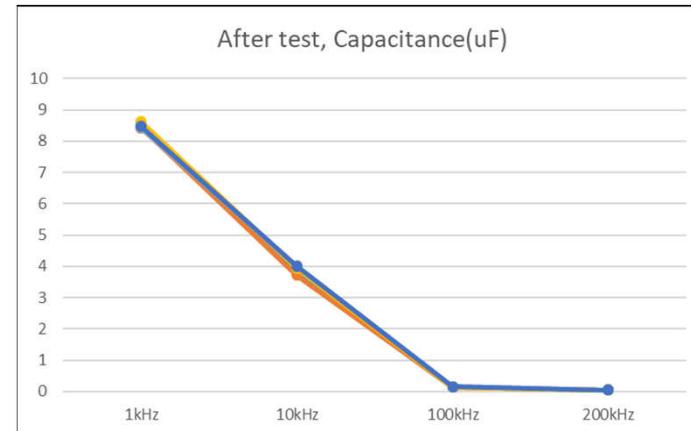
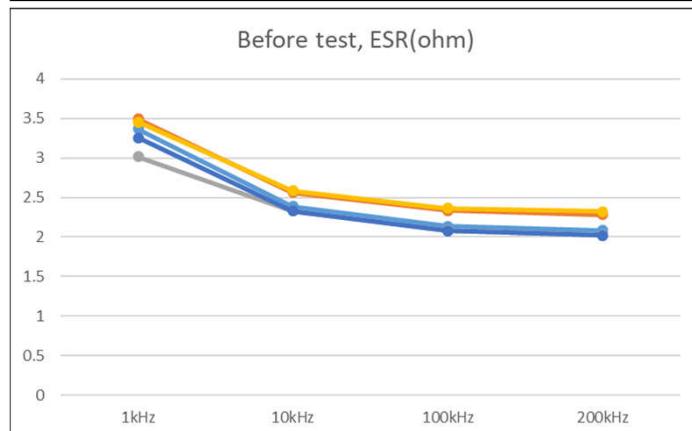
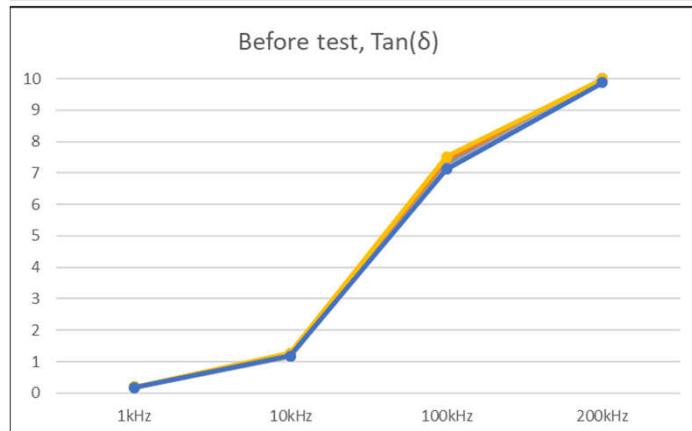
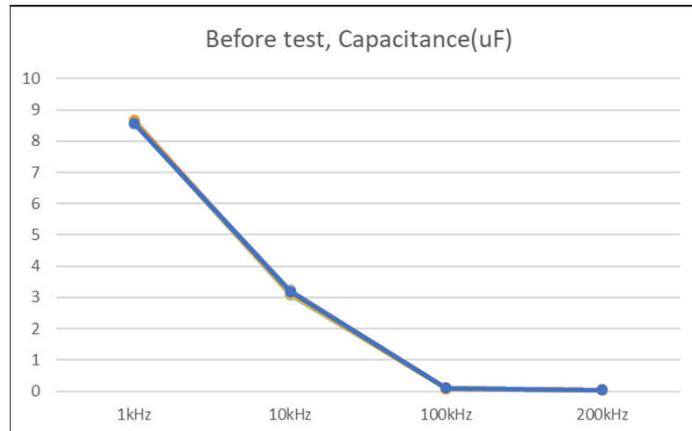
A社

High temp. and high humidity test



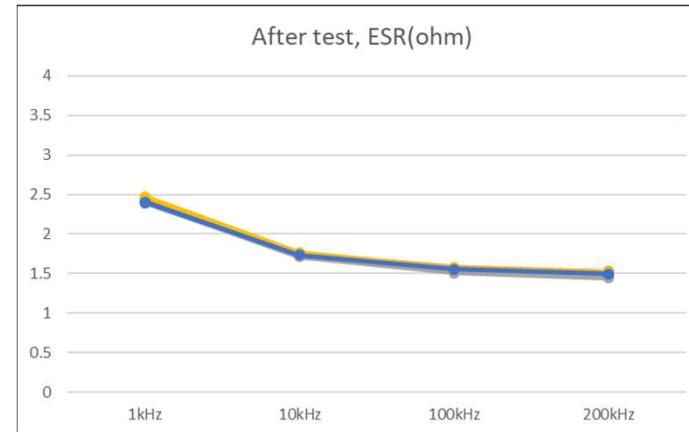
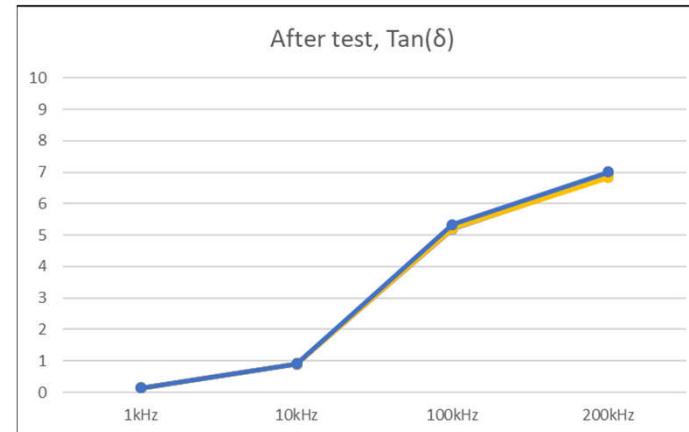
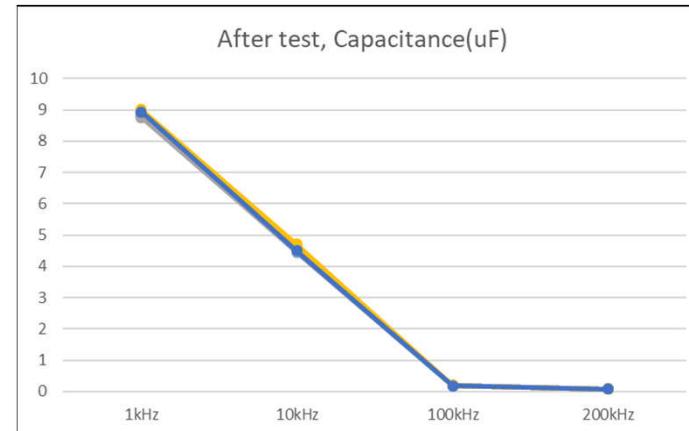
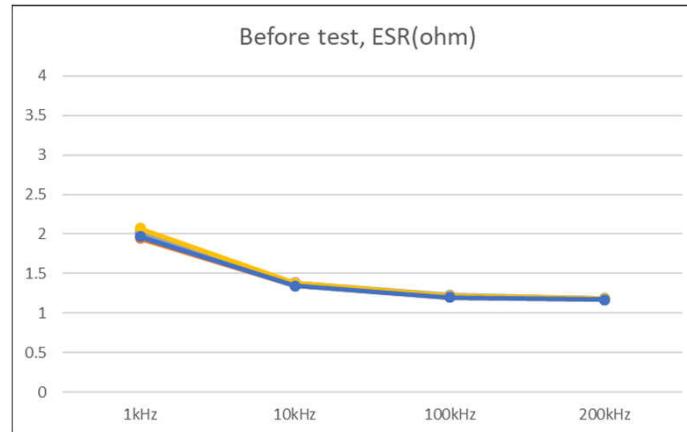
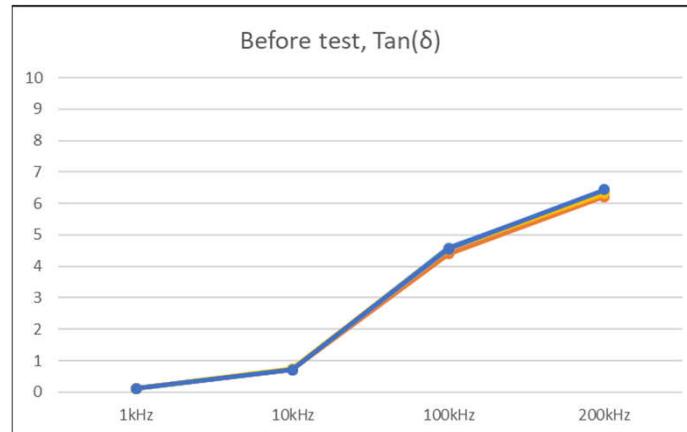
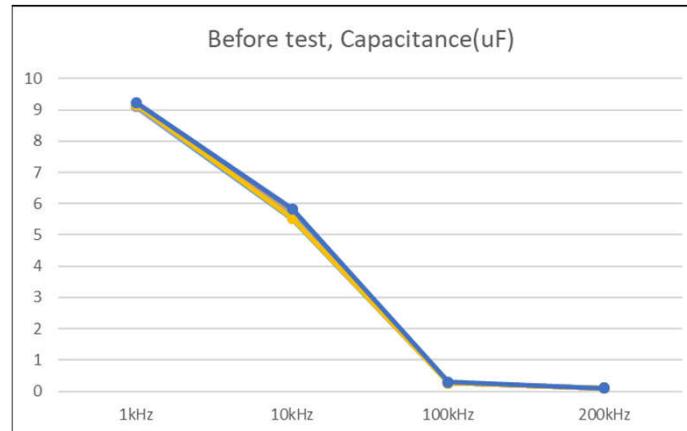
B社

High temp. and high humidity test



C社

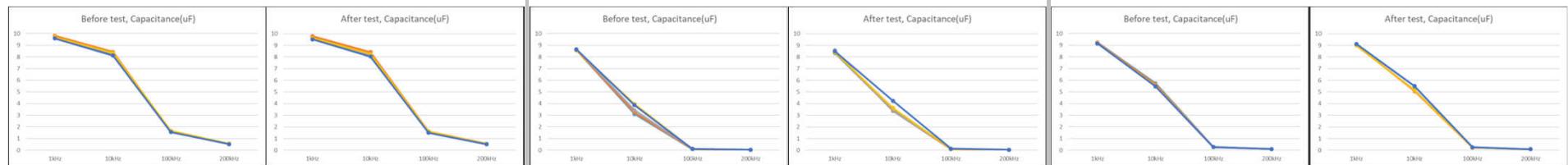
High temp. and high humidity test



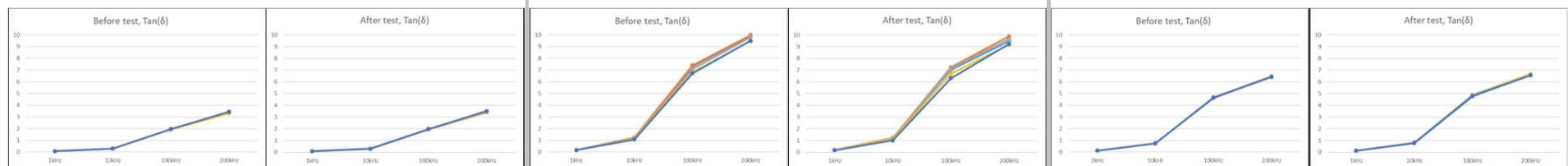
A/B/C社

Thermal shock test

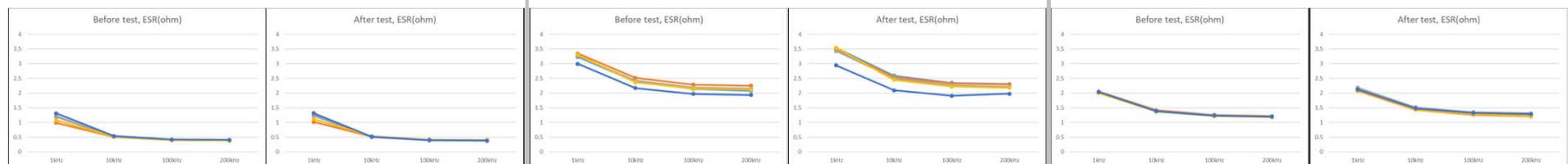
Capacitance(uF)



Tan(δ)

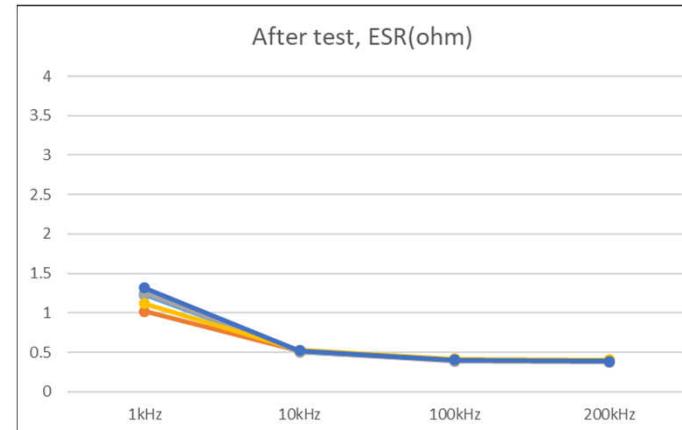
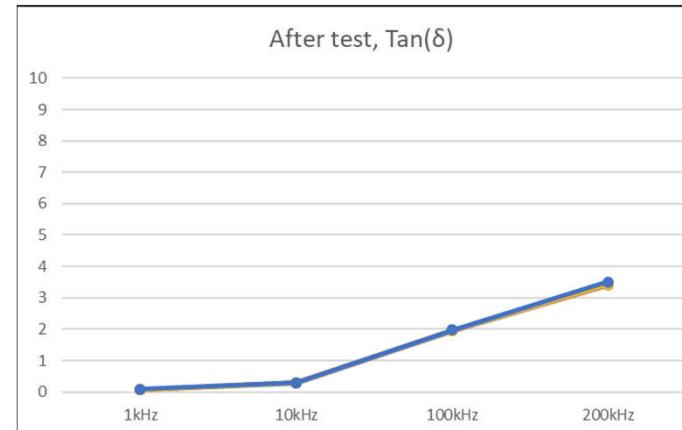
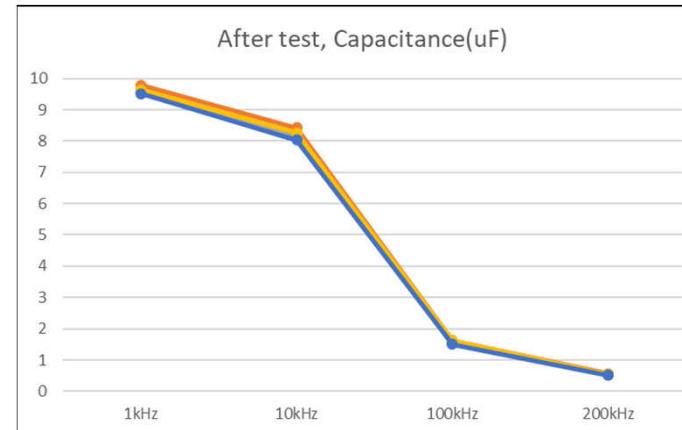
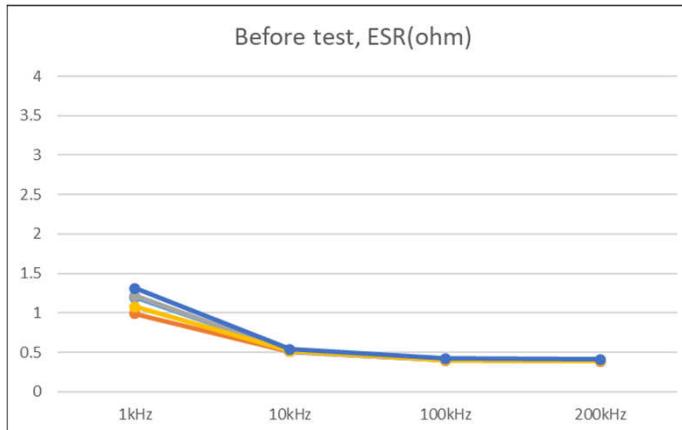
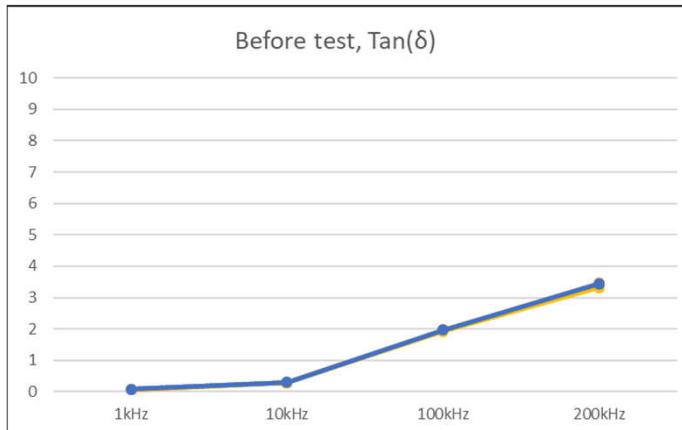
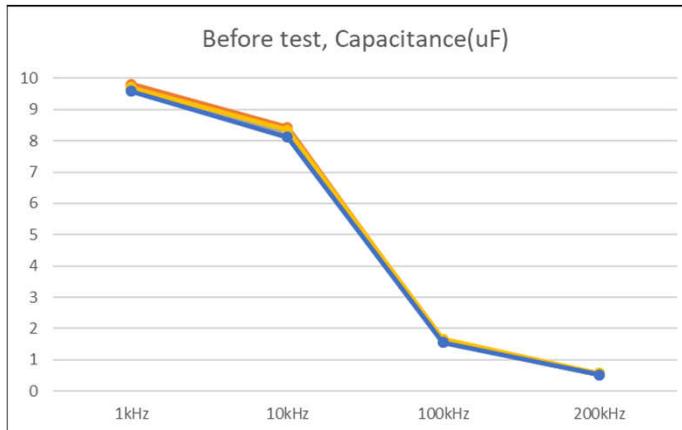


ESR(ohm)



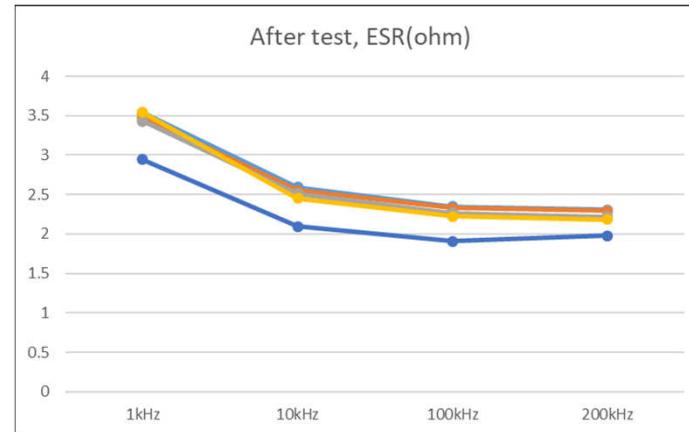
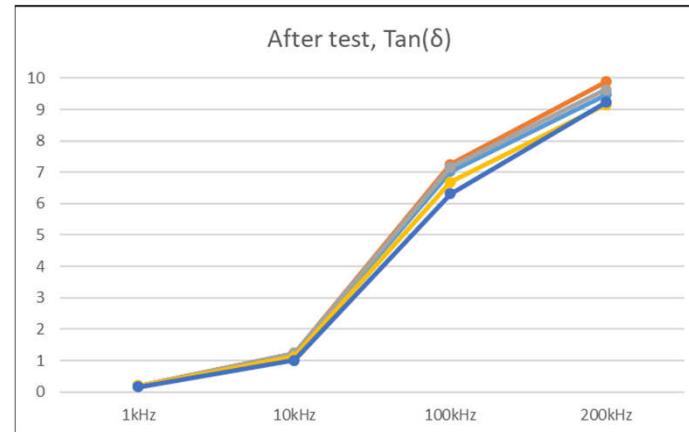
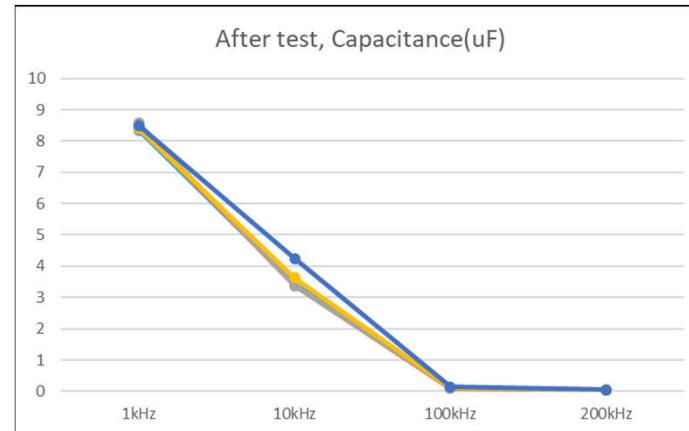
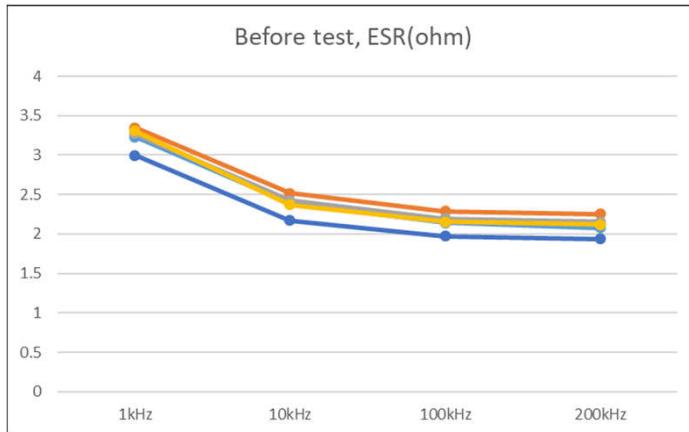
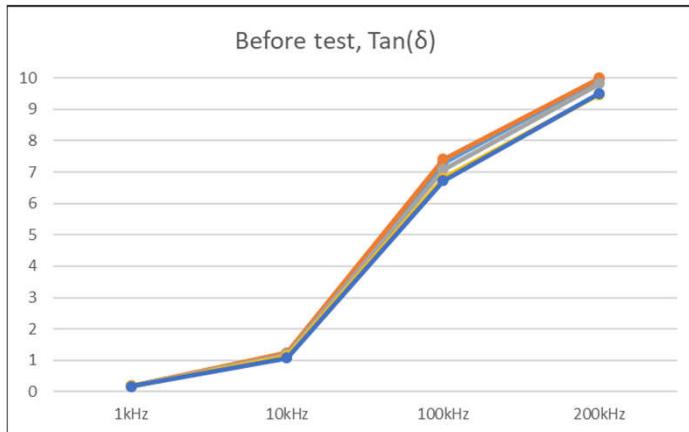
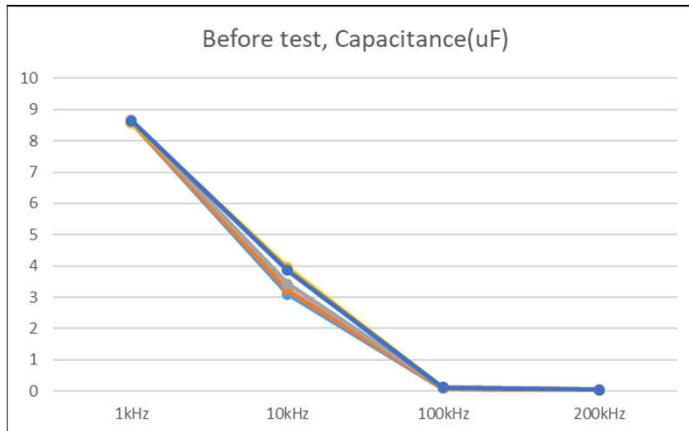
A社

Thermal shock test



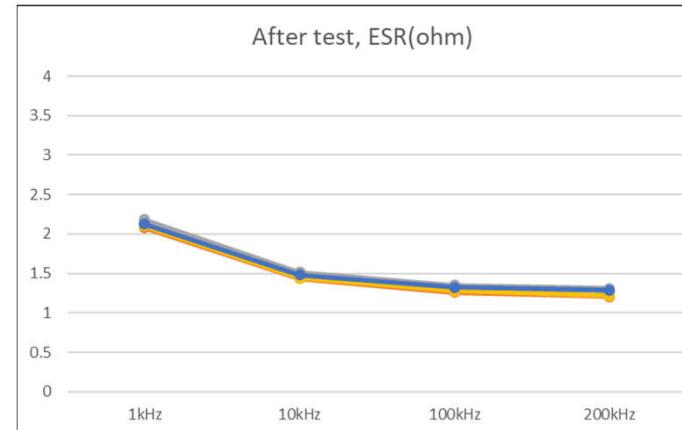
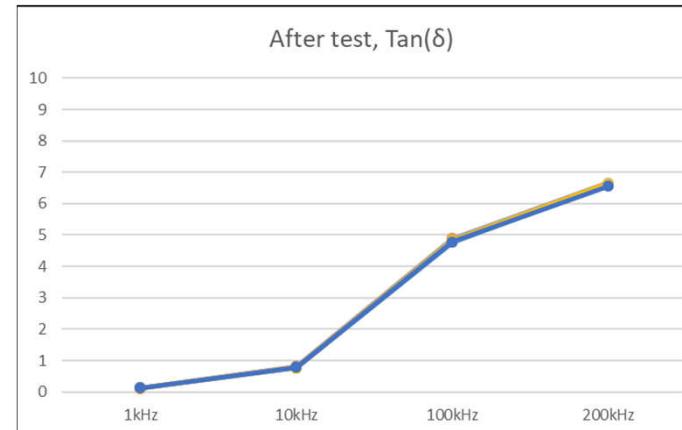
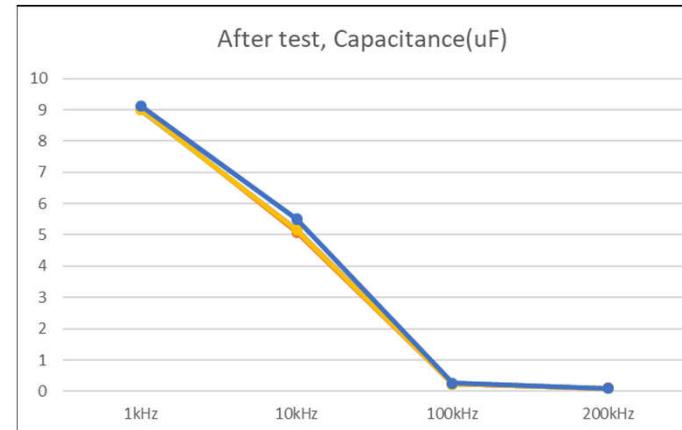
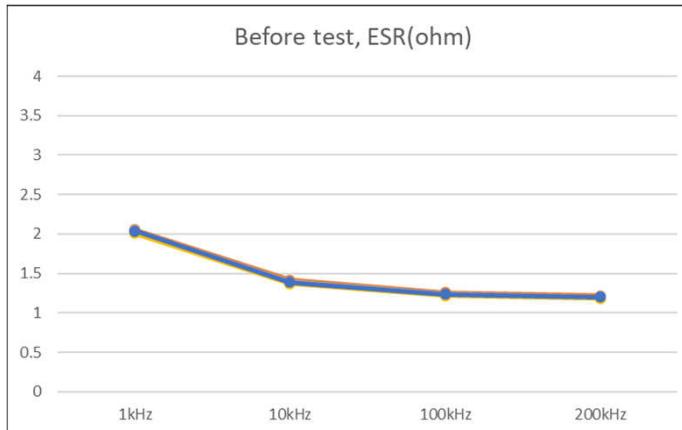
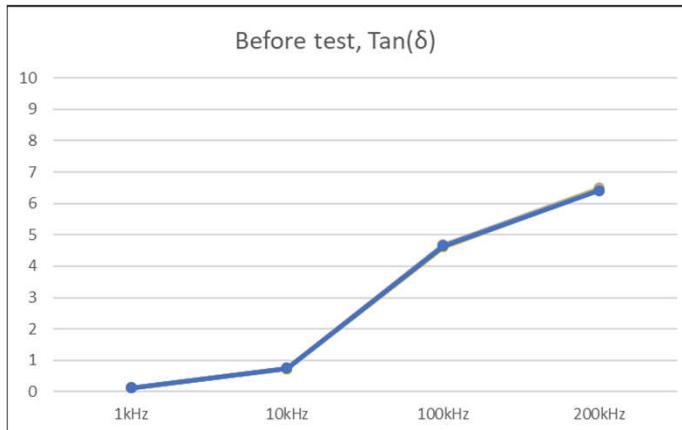
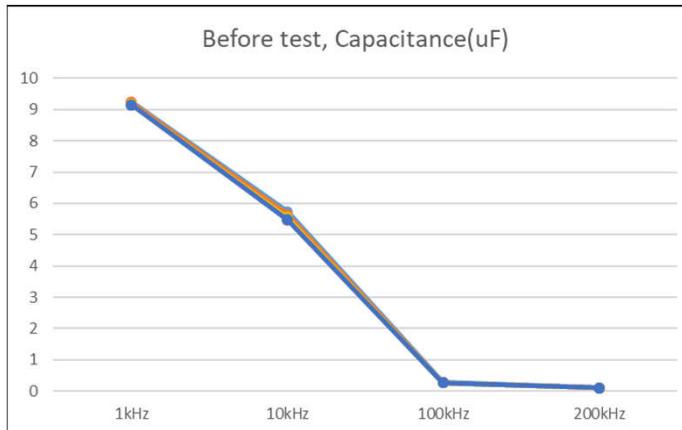
B社

Thermal shock test



C社

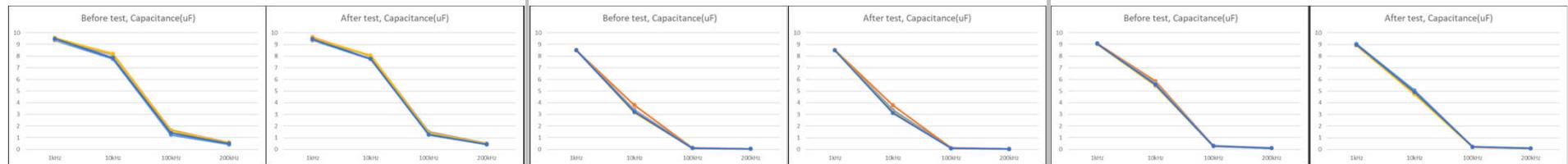
Thermal shock test



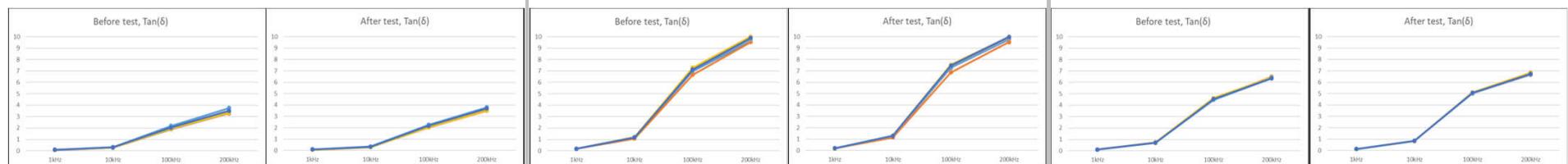
A/B/C社

Surge test

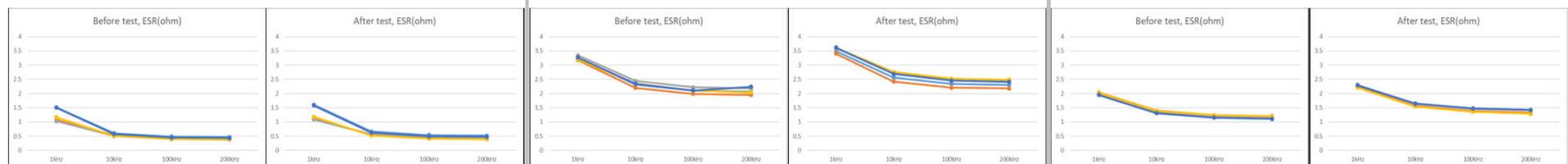
Capacitance(uF)



Tan(δ)

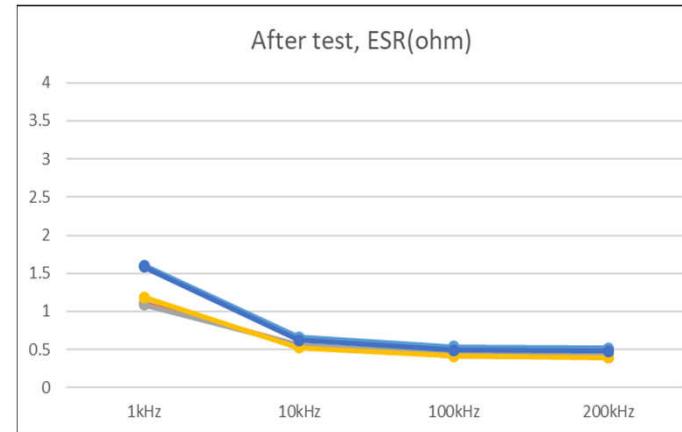
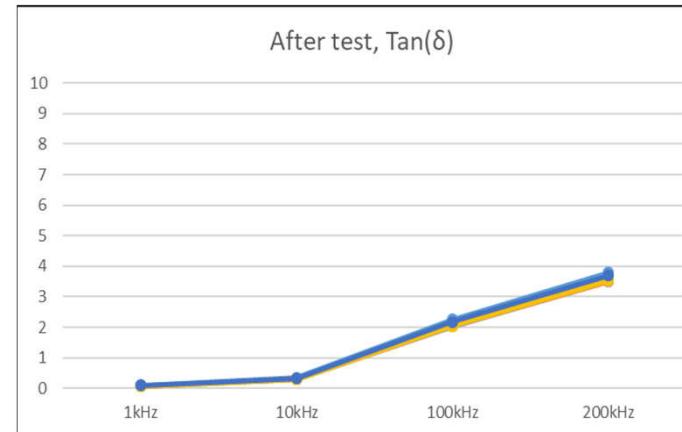
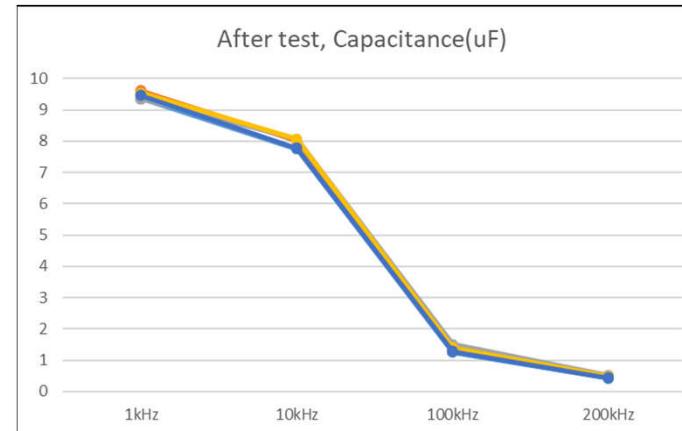
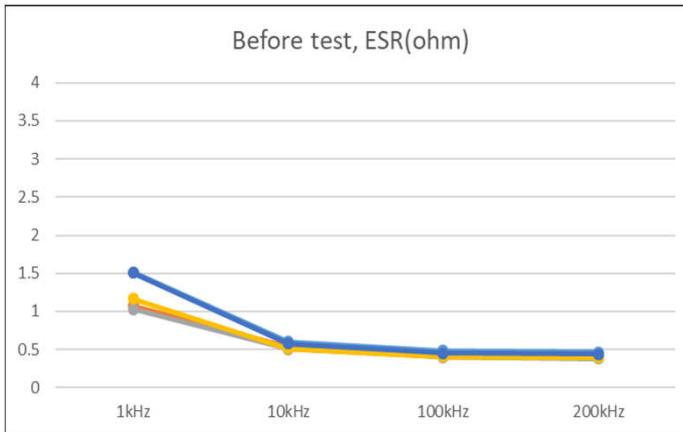
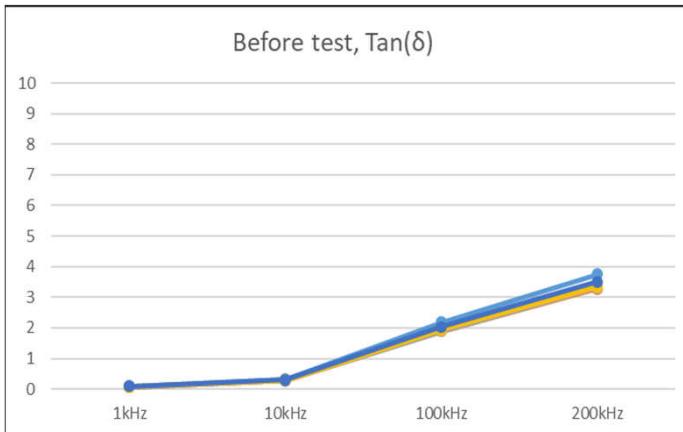
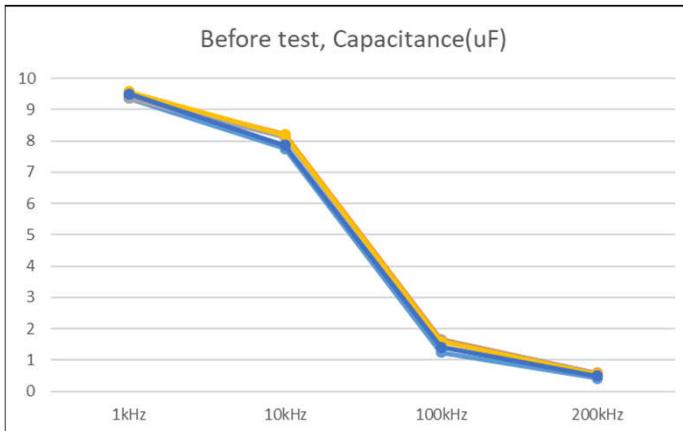


ESR(ohm)



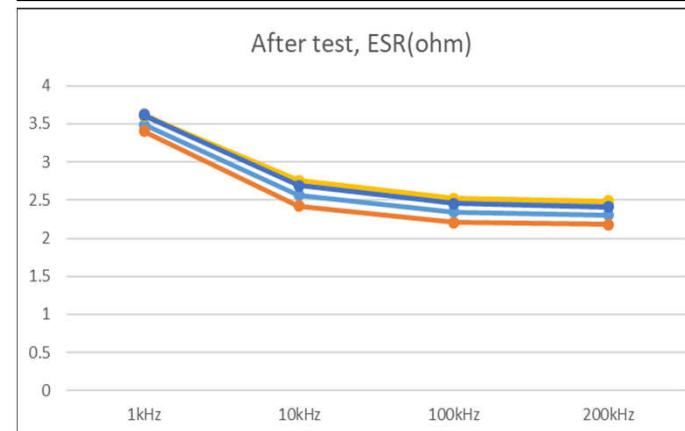
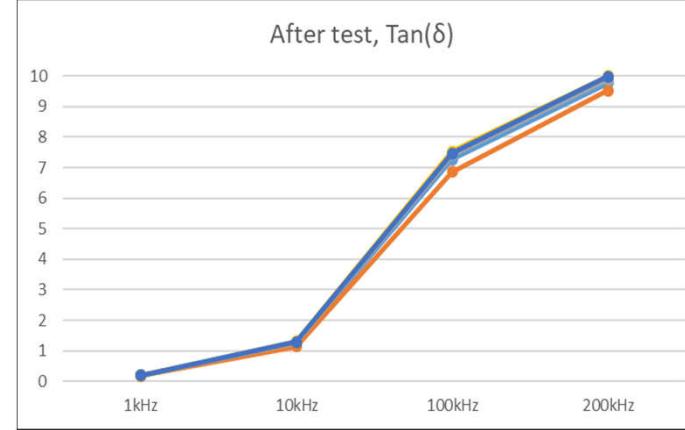
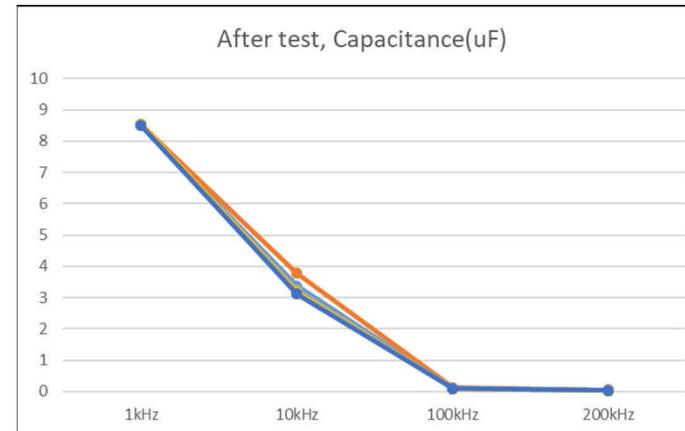
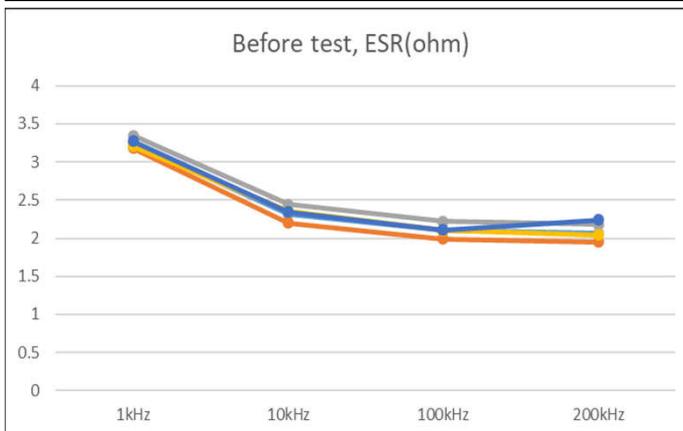
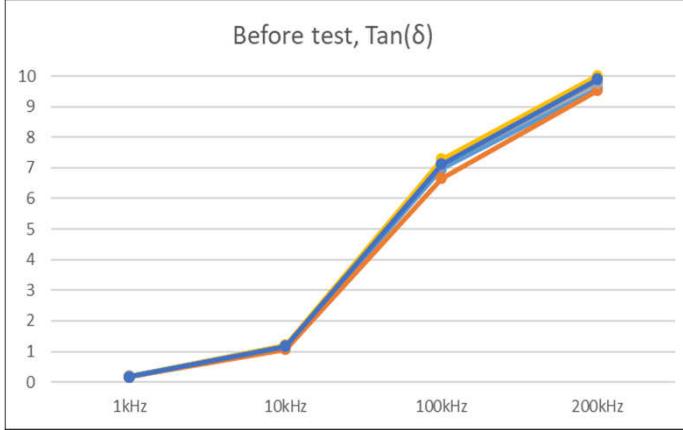
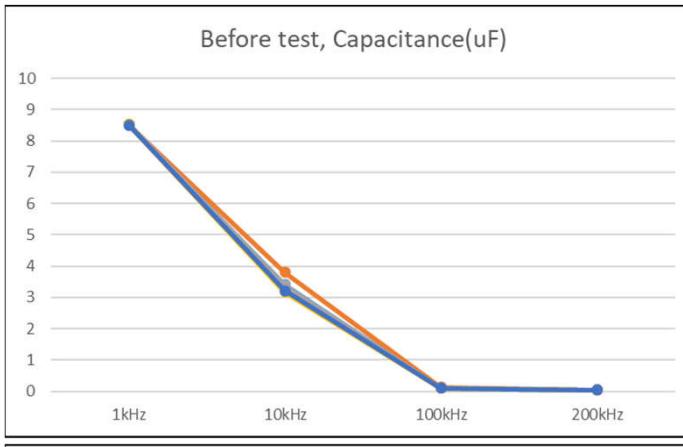
A社

Surge test



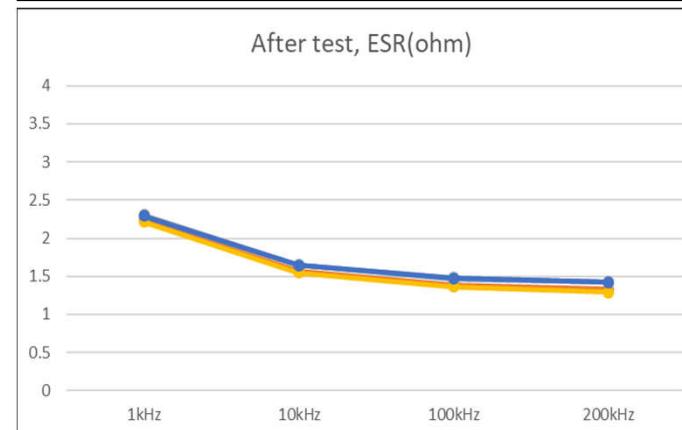
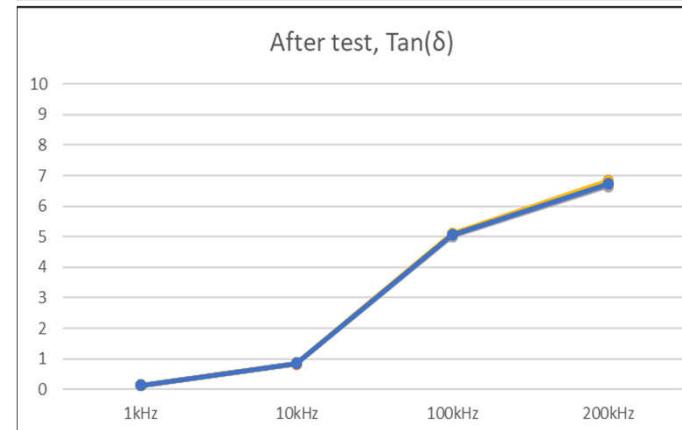
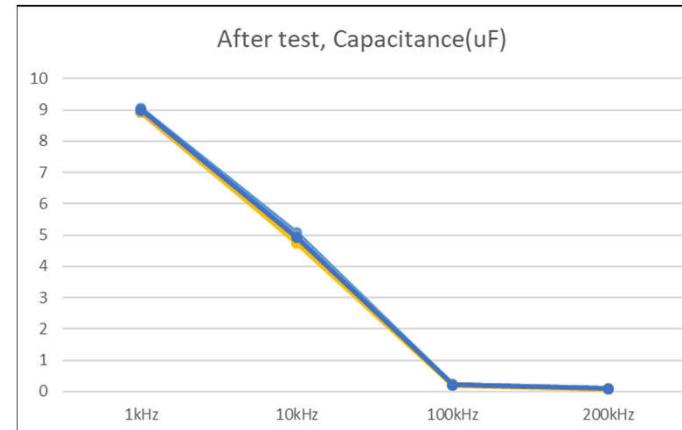
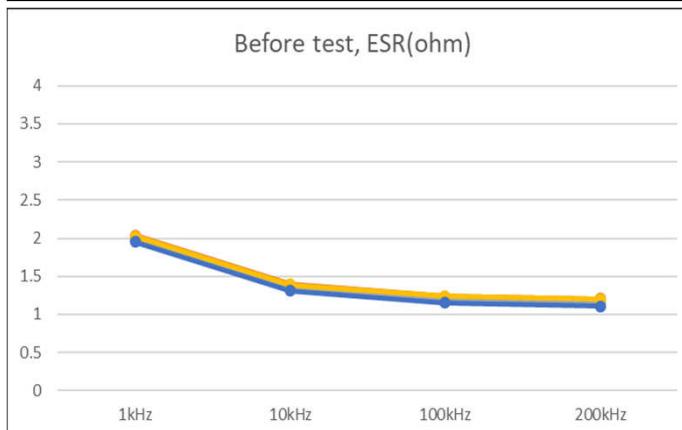
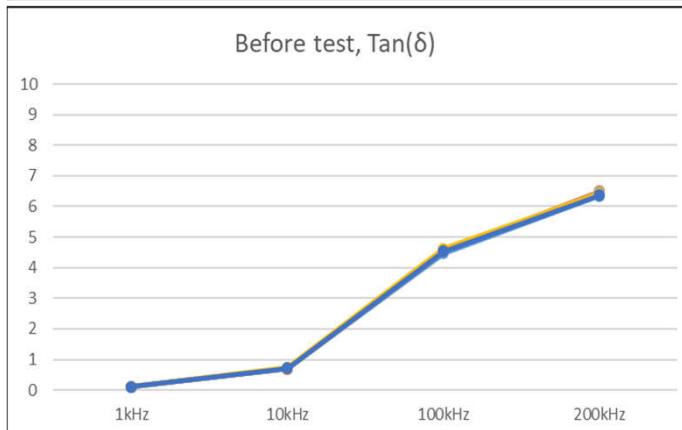
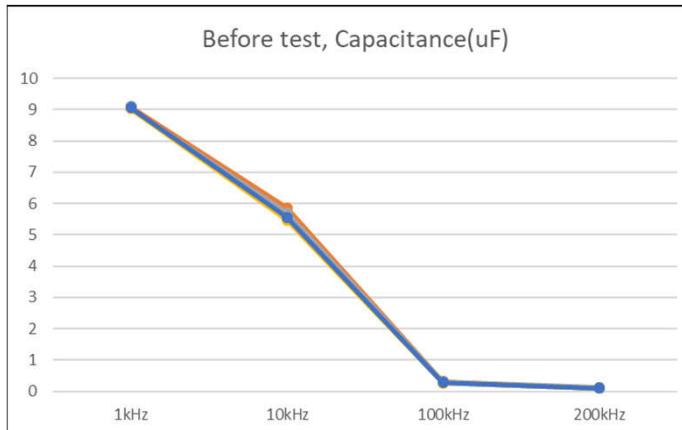
B社

Surge test



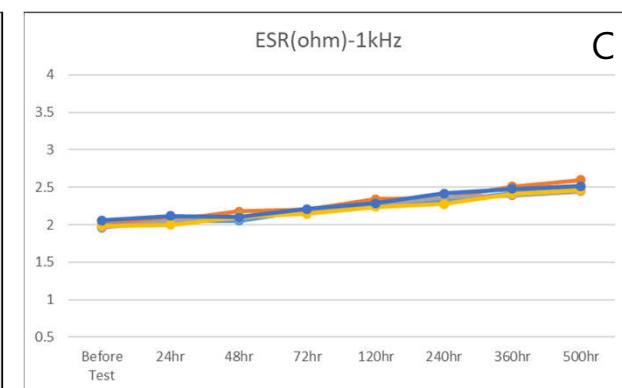
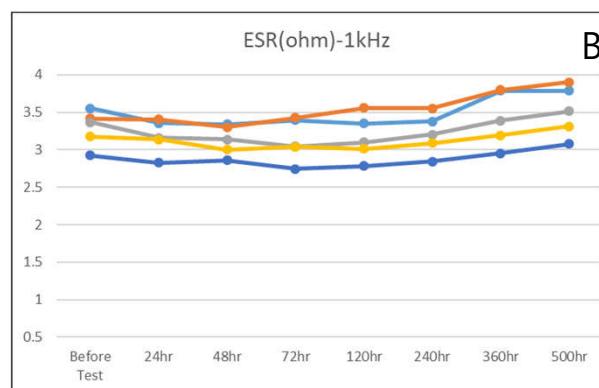
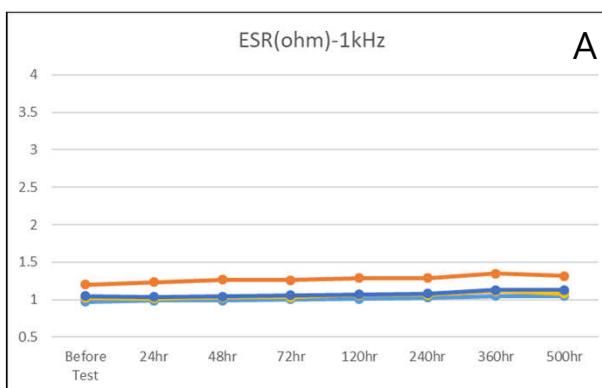
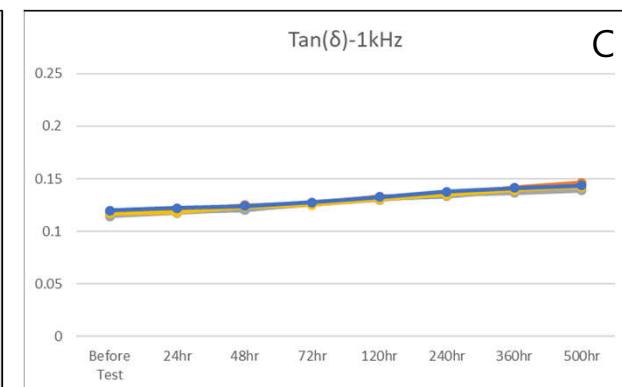
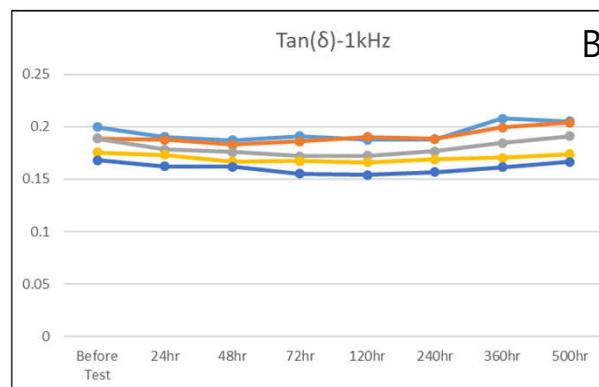
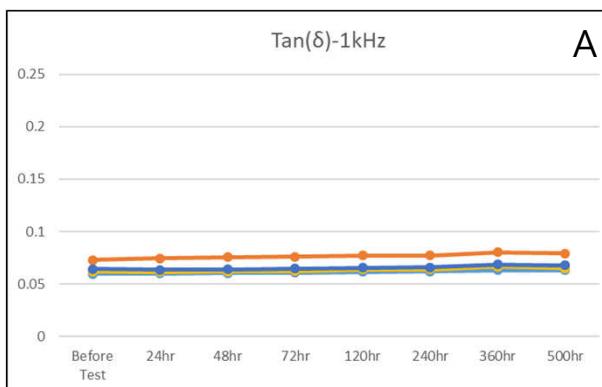
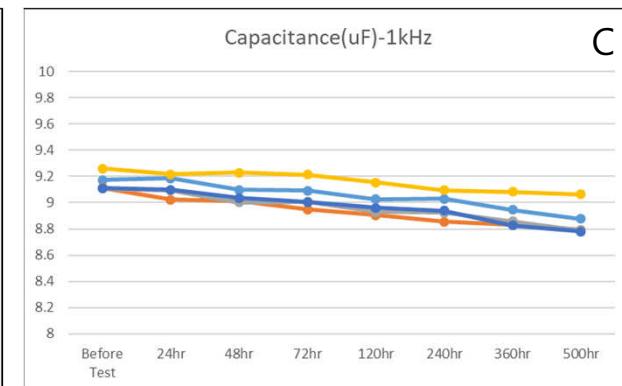
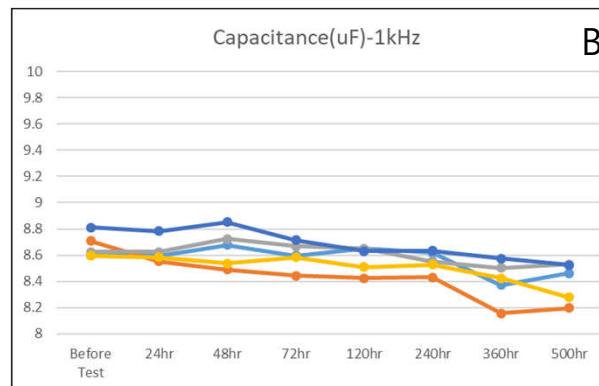
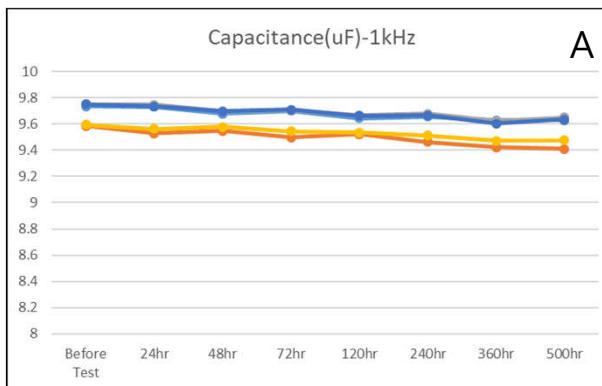
C社

Surge test



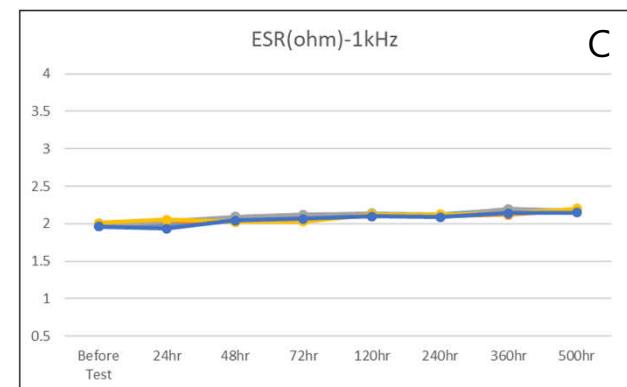
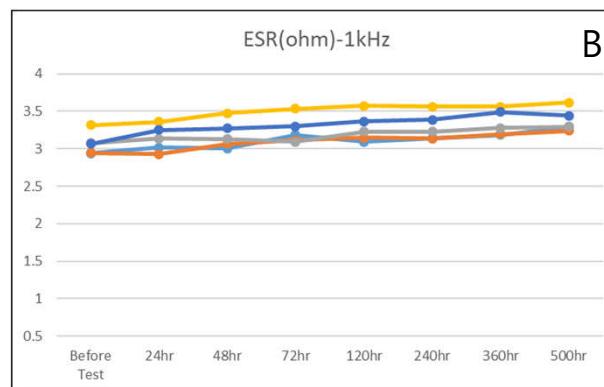
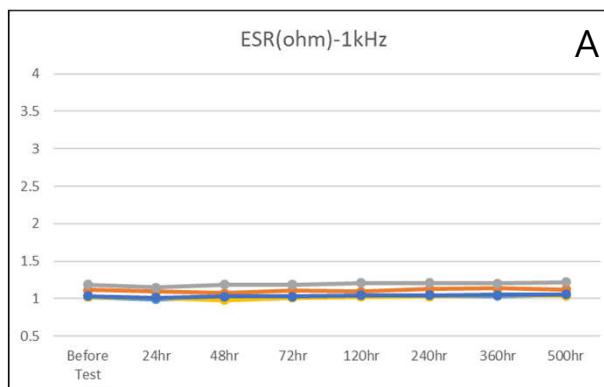
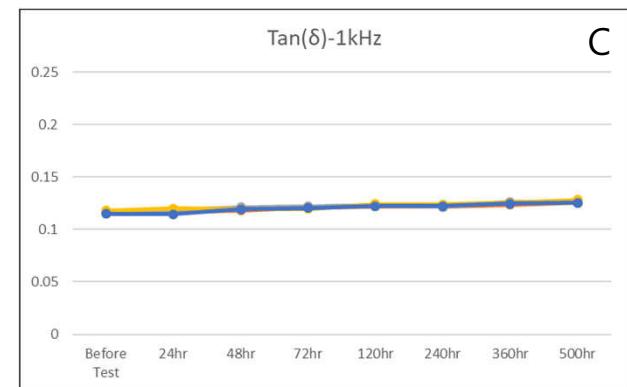
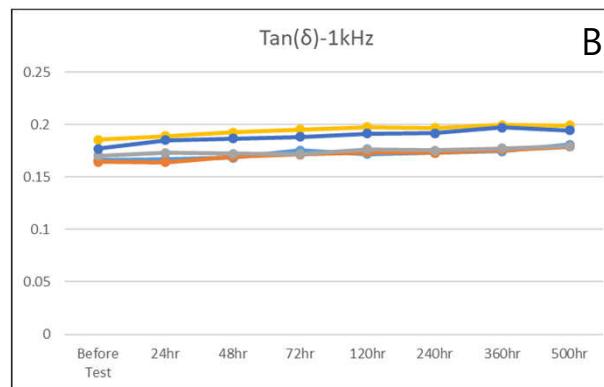
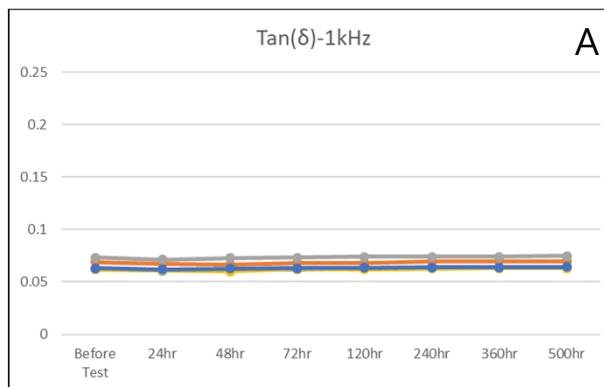
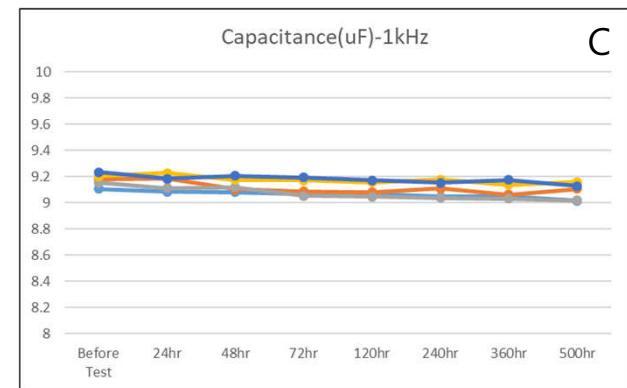
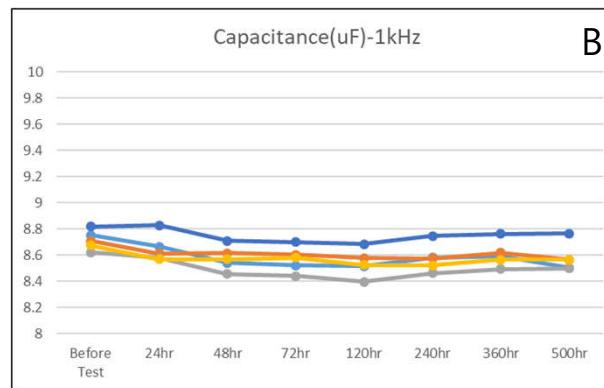
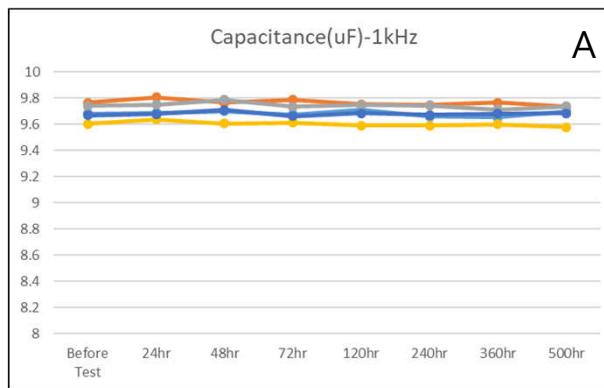
A/B/C社

High temperature test



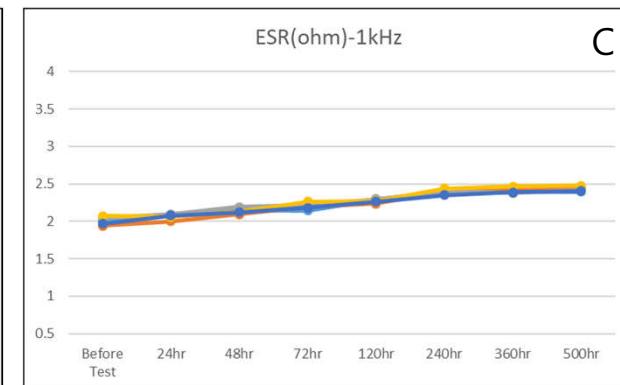
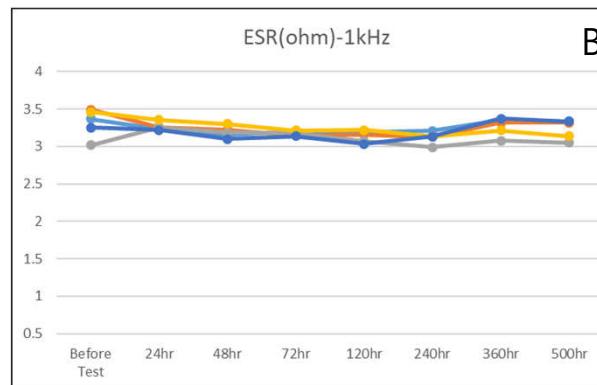
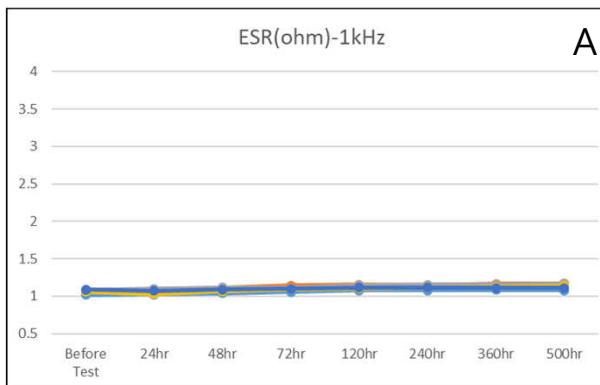
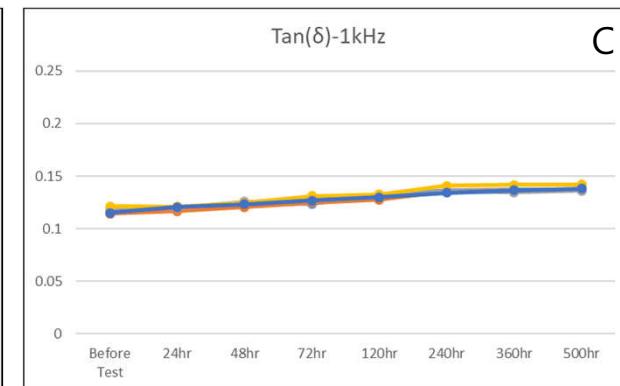
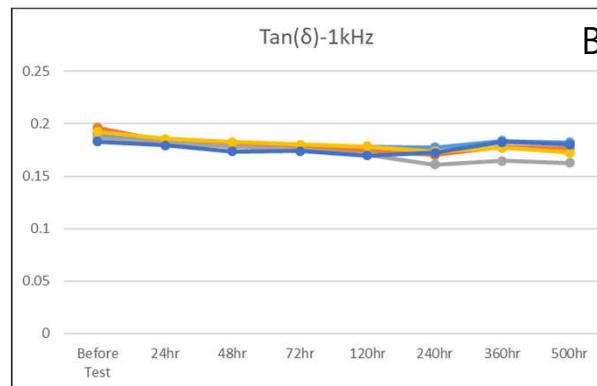
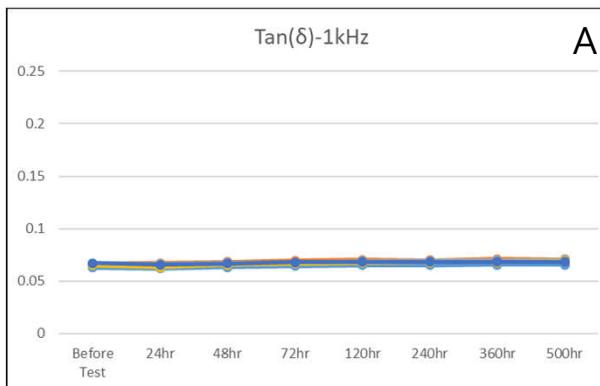
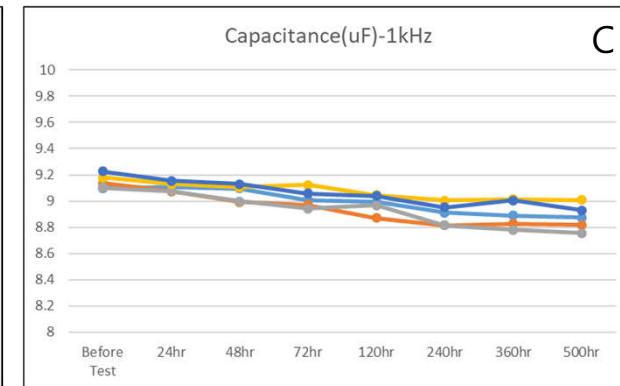
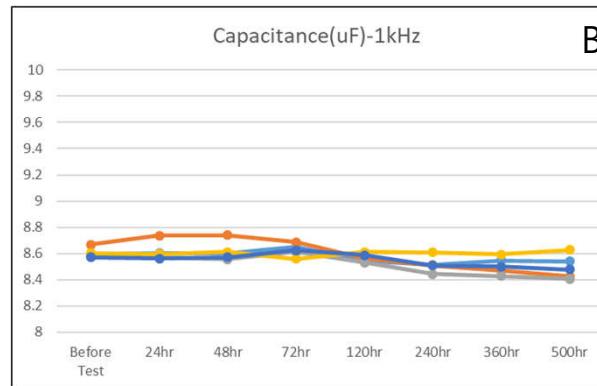
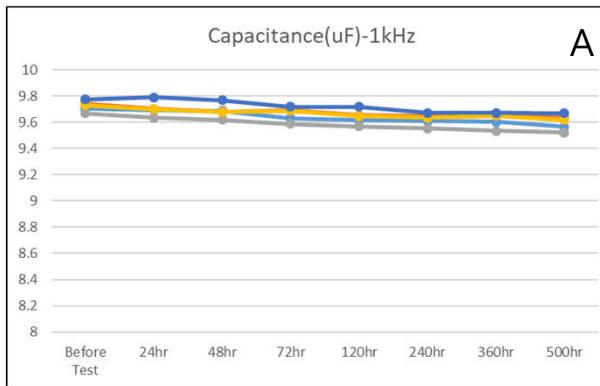
A/B/C社

Low temperature test



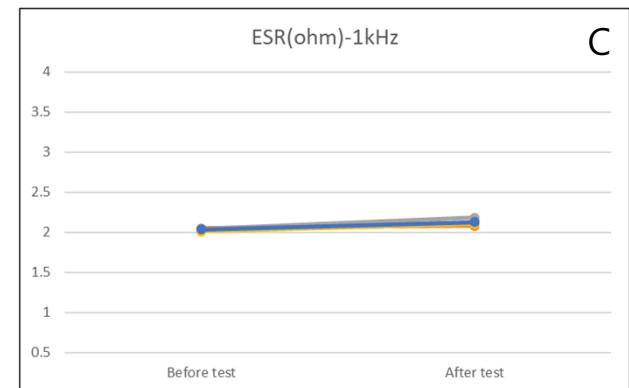
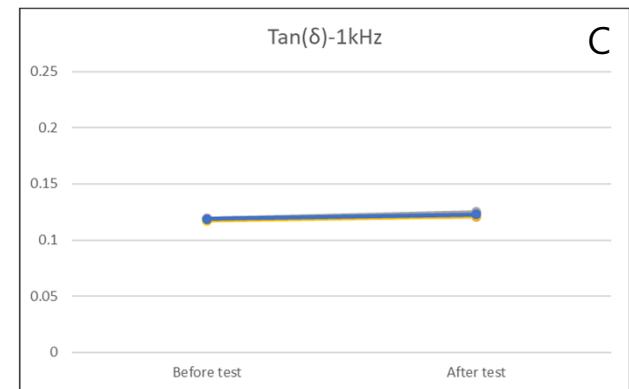
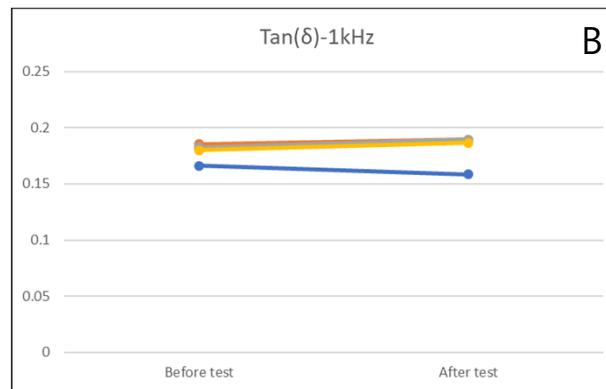
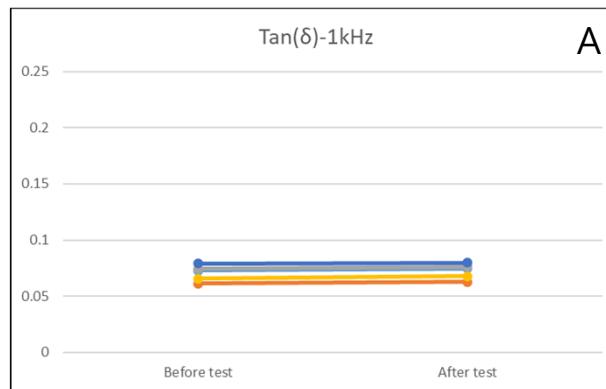
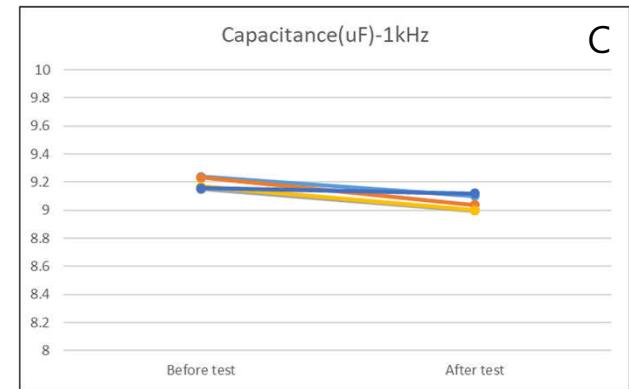
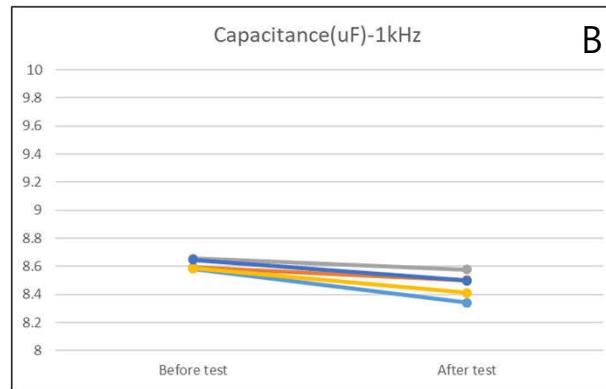
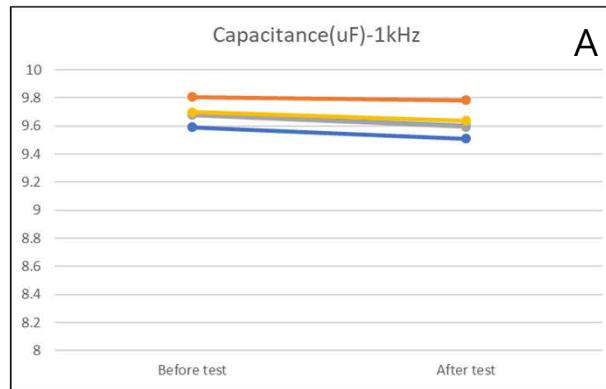
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High temp. and high humidity test



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Thermal shock test



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Surge test

